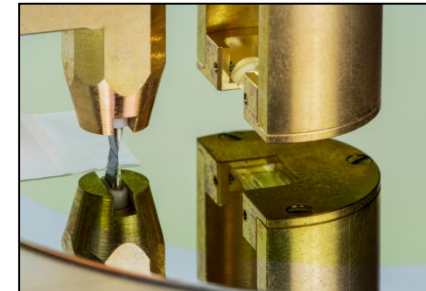
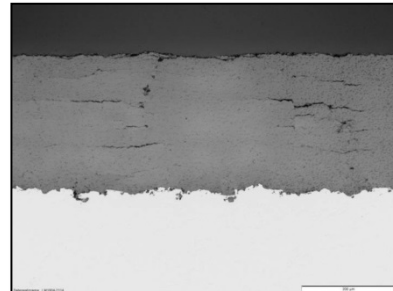
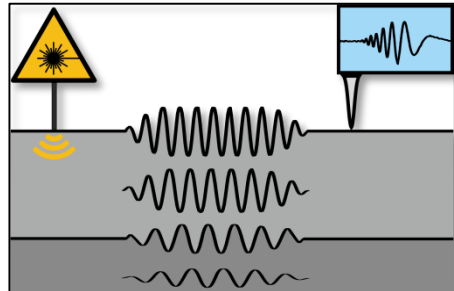
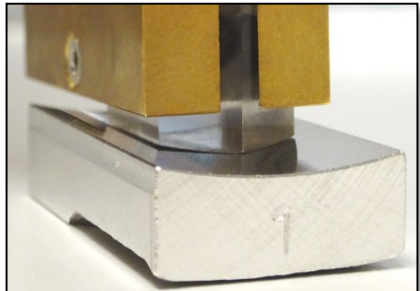
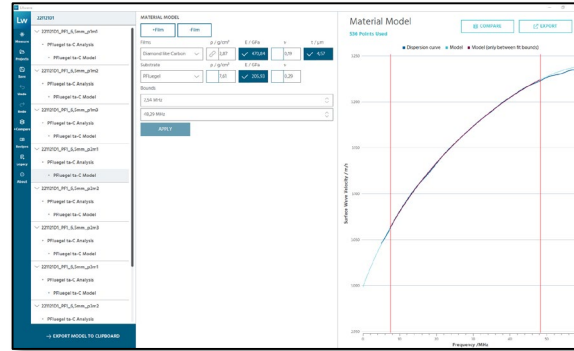
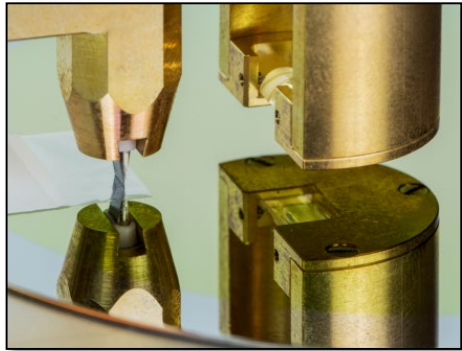


# LWave – Non-destructive characterization of coatings and material surfaces by laser-induced surface acoustic wave spectroscopy

Fraunhofer Institute for Material and Beam Technology IWS, Germany



# LWave – at a glance



## LWave – Our one-of-a-kind measurement technology offers

- Access to surface material properties: Non-destructive, quick with highest accuracy
- For academia: unique research options for material science and solid state physics
- For industry: Easy quantification of surface properties in less than one minute
- Custom solutions for research, quality control, analysis and automation
- Fully integrated software for measurement and analysis

## Facts and numbers

Complies with EN 15042-1:2006  
30+ systems world wide  
30+ years of experience  
70+ peer reviewed contributions  
2000+ citations  
R&D 100 award

# Contents

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## Introduction

Application Overview and How it works

## Method

Measurement Principle, Evaluation Concepts, Material Models

## Development and Background

Development, History

## Case Studies

Semiconductor, PVD, Thermal Spray, Laser Cladding, Surface treatment, Comparison with Indentation, ...

## Methodical Aspects

Roughness, Sample curvature, Comparison with Nanoindentation

## Worldwide Contact

# Introduction

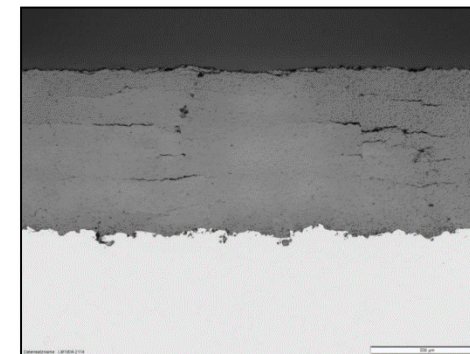
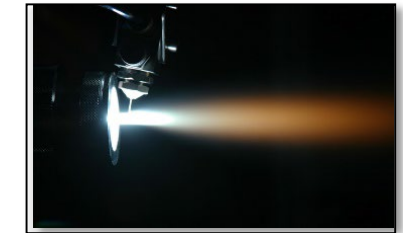
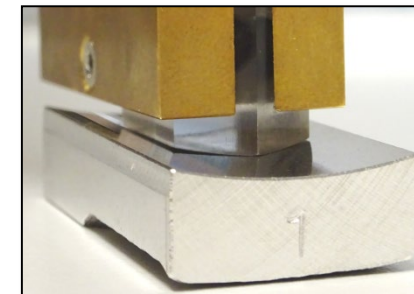
# Components and technologies

## Mechanical properties of coated components


- Cylinder liner coatings (APS, wire arc spraying, ...)
- Electric heaters (thermal sprayed coatings)
- Brake disk coatings (laser cladding)
- Heavy duty gear parts (cemented carbide coatings)
- 3D-printed metal components (SLM)
- Piston pins, tappets, chain components (PVD)
- And many more....

## For R&D and quality control

- Effective Modulus (Pores, cracks, voids, delamination)
- Thickness
- Homogeneity
- Fast and effective – high throughput screening

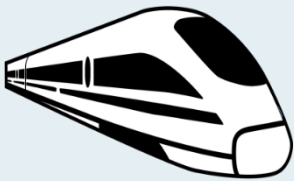


# Highlights



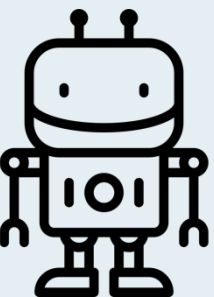
**non-destructive**

John Caserta, CC BY 3.0



**fast**  
( $< 60$  s)

www.Pixabay.com Free Licence



**fully automatable**

Freepik, CC BY 3.0

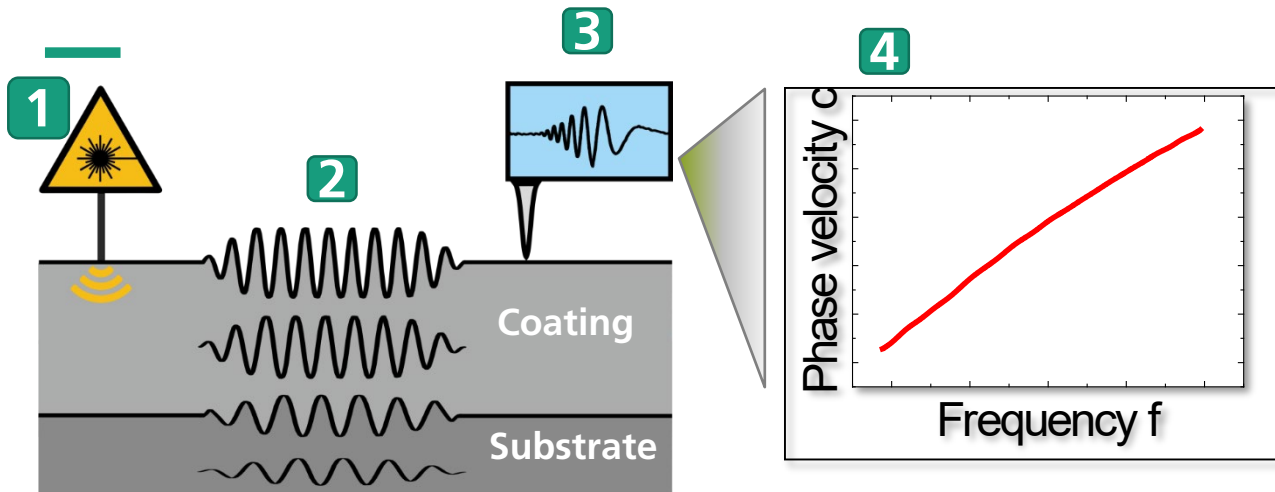
## Basics

- LAwave® - Laser-induced surface acoustic waves spectroscopy
- Can access mechanical properties of coatings and surfaces
- Integral and effective mechanical information
- including pores, cracks and delamination
- Numerous applications for industrial quality control and R&D

## Advantages over indentation

- Faster measurement, no calibration, less consumables
- Higher precision, more and integral information
- Measures on rough surfaces
- True effective modulus: no plastic deformation, no compression of cracks, pores and defects

# How it works - Overview



- (1) Broadband surface acoustic waves (SAW) induced by short laser pulses
- (2) SAW propagation, velocity depends on frequency
- (3) SAW measurement: piezoelectric element → digitizing oscilloscope

- (4) Fourier transformation yields velocity over frequency (dispersion curve)
- (5) Dispersion curve analysis using different evaluation strategies

5

Material model

film 4:	$E_4, \nu_4, \rho_4, d_4$
film 3:	$E_3, \nu_3, \rho_3, d_3$
film 2:	$E_2, \nu_2, \rho_2, d_2$
film 1:	$E_1, \nu_1, \rho_1, d_1$
substrate	isotropic: $E, \nu, \rho$

Calibration data

Ok/not ok boundaries

## Possible results

- Young's Modulus
  - Density
  - Depth of: Nitriding layer, Case-hardening, Damage layers
  - Porosity, crack density
  - Delamination
  - Build-up structure
  - Surface hardness
- .... Anything that affects your mechanical integrity of the material

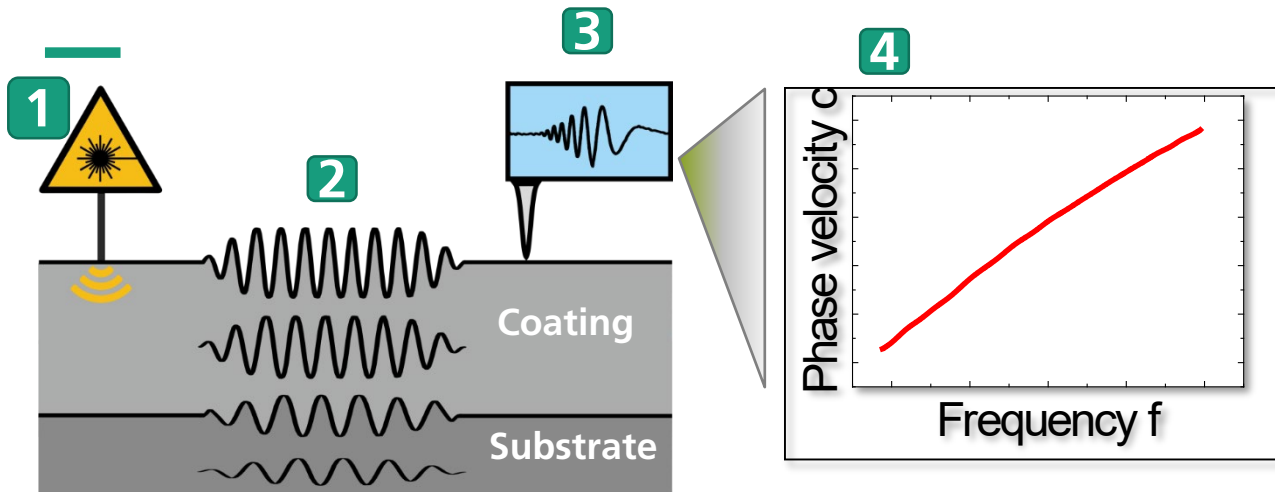


# Method

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# Method Overview



- (1) Surface acoustic wave (SAW) generation
- (2) SAW propagation through measured material volume
- (3) SAW measurement by piezoelectric element

- (4) Calculation phase velocity over frequency (dispersion curve)
- (5) Different analysis strategies

5

**Material model**

film 4:	$E_4, \nu_4, \rho_4, d_4$
film 3:	$E_3, \nu_3, \rho_3, d_3$
film 2:	$E_2, \nu_2, \rho_2, d_2$
film 1:	$E_1, \nu_1, \rho_1, d_1$
substrate	isotropic: $E, \nu, \rho$

**Calibration data**

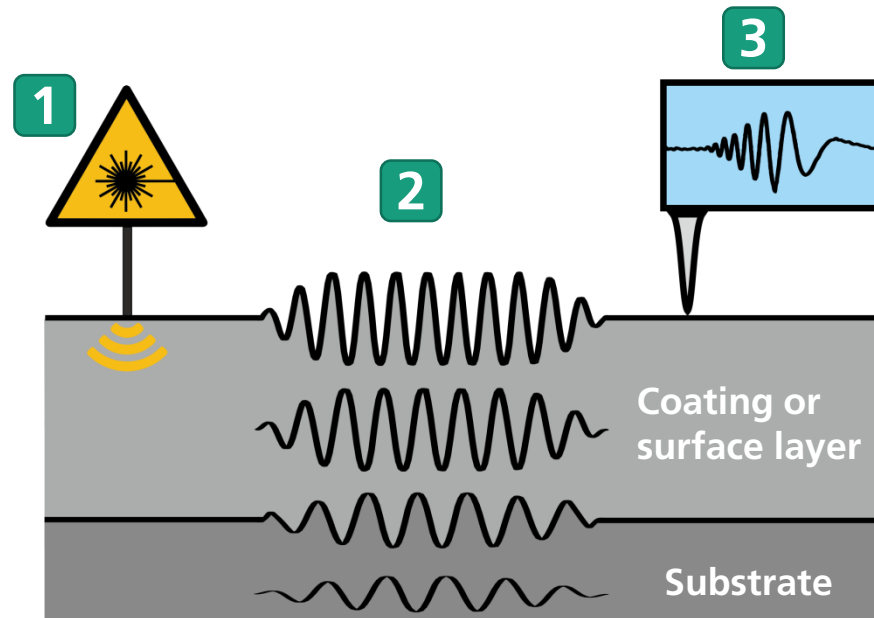
**Ok/not ok boundaries**

**Possible results**

- Young's Modulus
- Density
- Depth of: Nitriding layer, Case-hardening, Damage layers
- Porosity, crack density
- Delamination
- Build-up structure
- Surface hardness

.... Anything that affects your mechanical integrity of the material

# Surface wave excitation and measurement



## 1 SAW excitation

- Broadband surface acoustic waves (SAW) induced by short laser pulses

## 2 SAW propagation

- Penetration depth of SAW  $\approx$  wavelength
- SAW velocity  $c$  depends on frequency  $f$

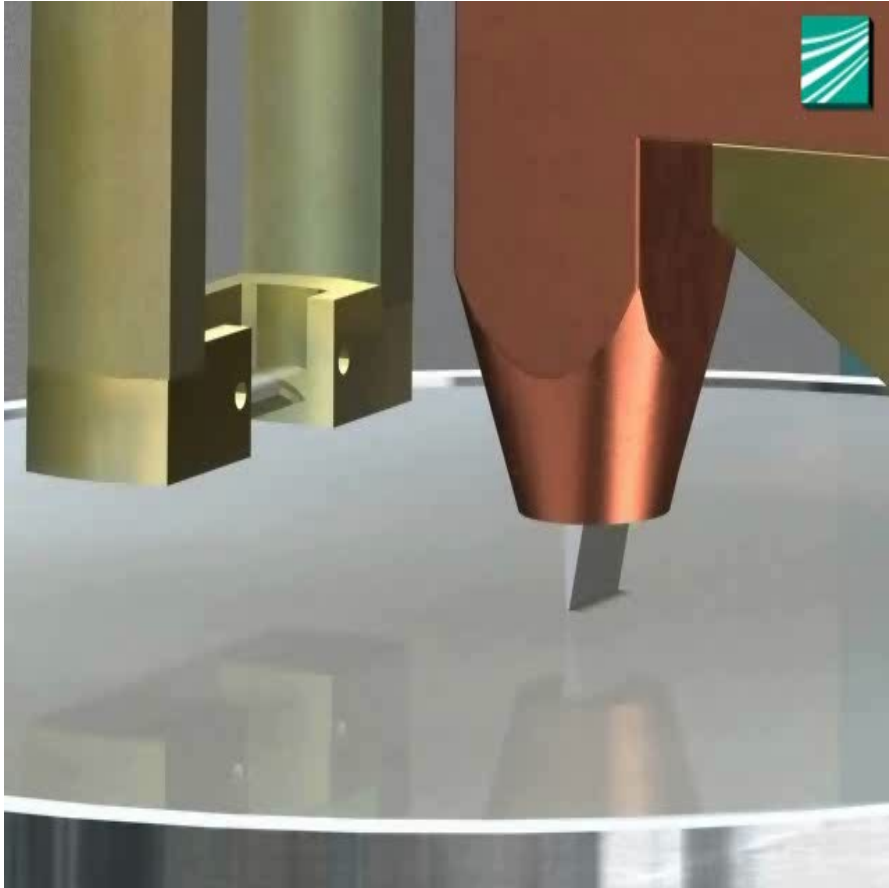
$$\lambda = c/f$$

$$c = c(f)$$

## 3 SAW detection

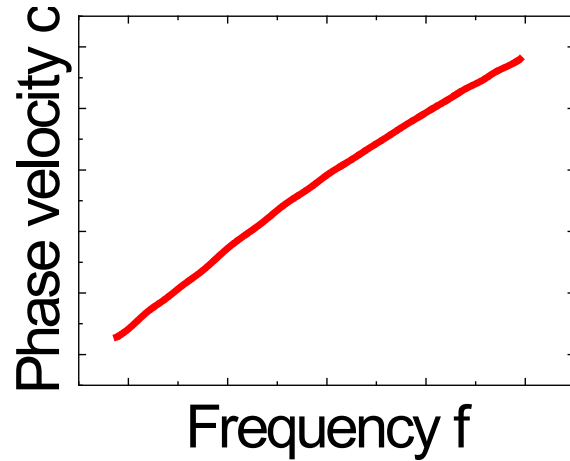
- Mechanical vibrations  $\rightarrow$  electrical signals
  - Wedge type sensor with piezoelectric foil for 20-250 MHz
  - Conventional ultra sound sensor for 1-20 MHz
- Oscilloscope measures impulse run-time

# Surface wave excitation and measurement - Video

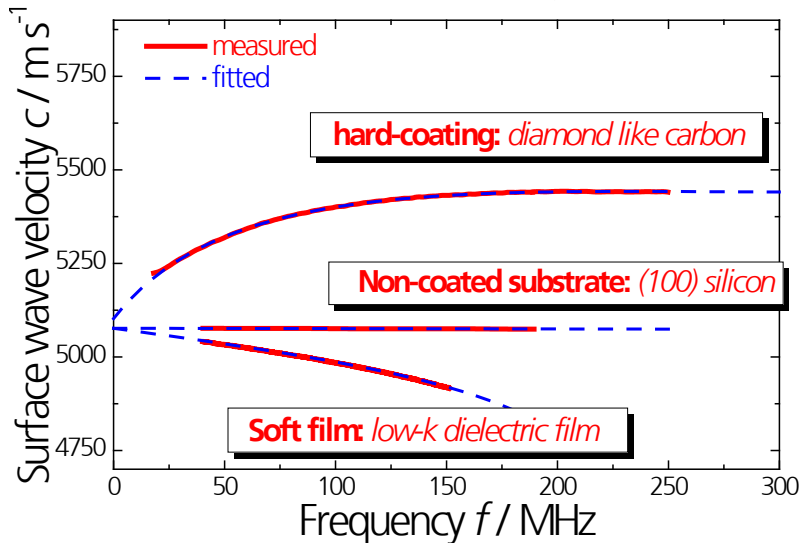


# Evaluation of Measurement

4



5



## 4 Measuring procedure and data analysis

- Variation of propagation distance  $x$
  - FT of the detected signals
- Phase spectra  $\Phi(f)$  for different distances and phase velocity  $c(f)$

$$c(f) = \frac{(x_2 - x_1)2\pi f}{\Phi_2(f) - \Phi_1(f)} = \text{dispersion curve}$$

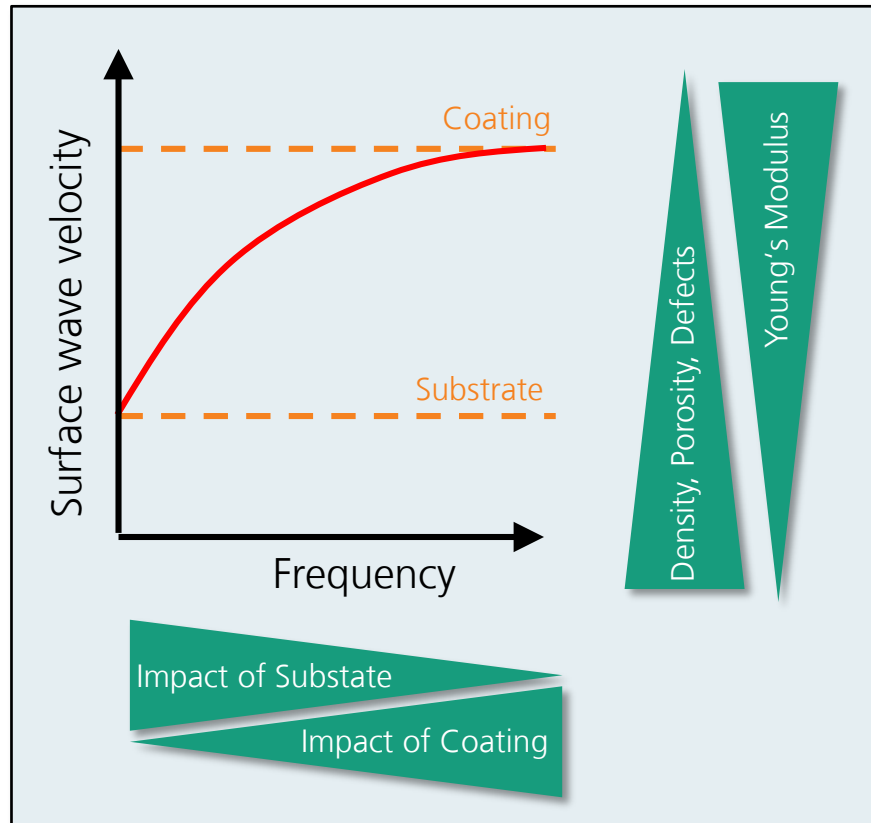
- Shape of the dispersion curve  $c(f)$  depends on elasticity, density and film thickness

## 5 Approaches to get film properties

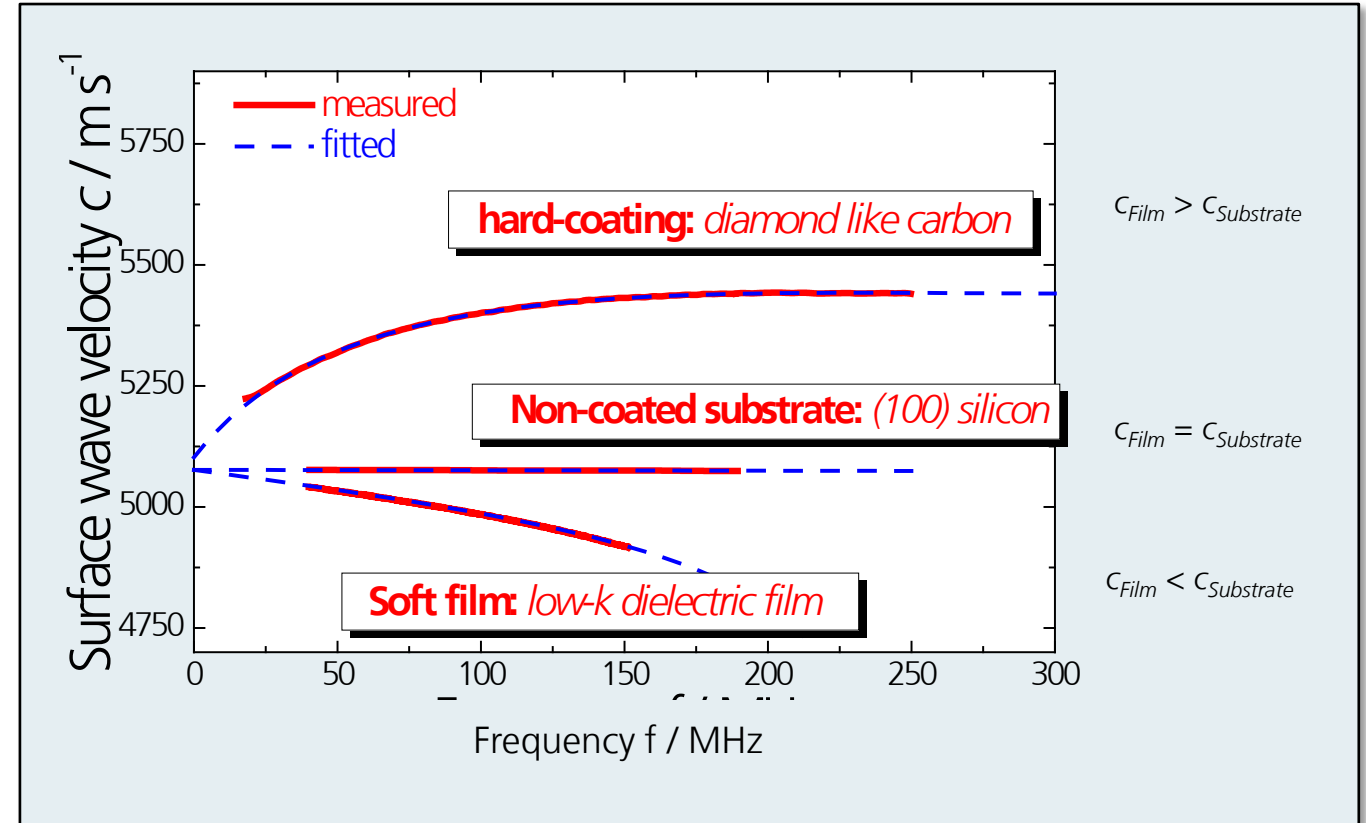
- Fitting measured curve to theory, using a material model
- Calibration with another method
- Defining ok/not ok boundaries from known samples
- Using regression fitting and KI with known samples

# Dispersion Curve – Influence of Material System

## Schematic influence



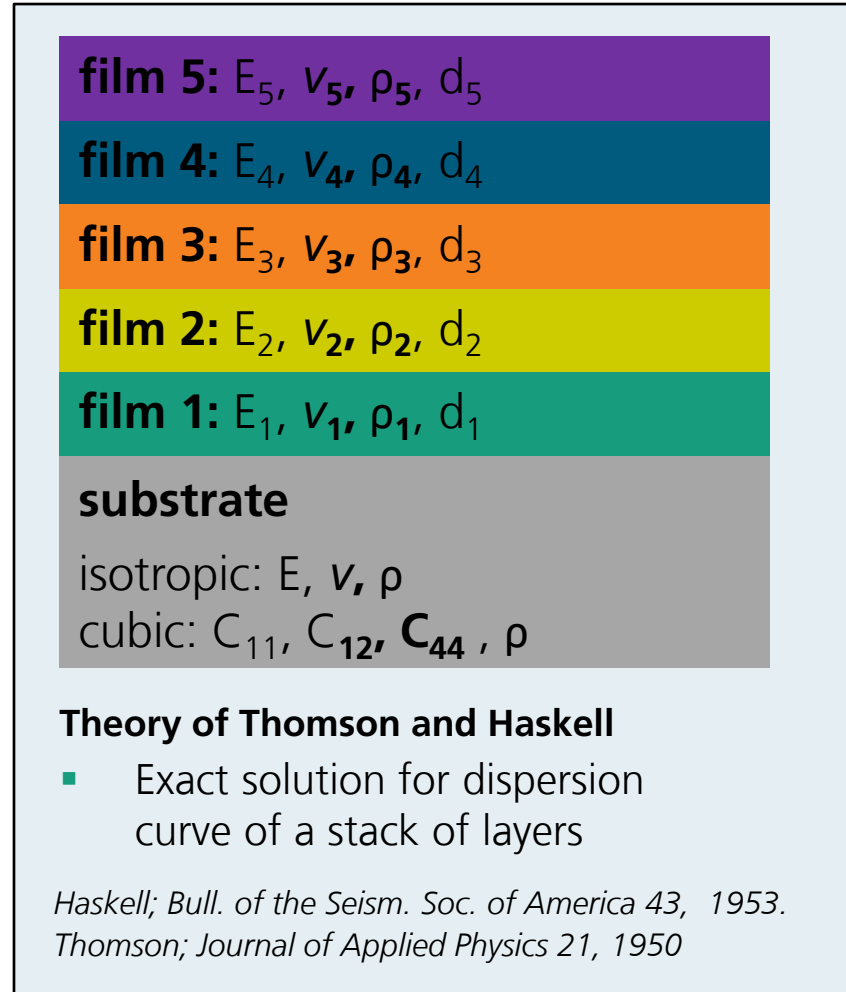
## Actual influence measured on coated silicon wafer



# Dispersion Curve Analysis – Multilayer Material Model

## Multilayer Model by Haskell and Thomson

- Is able to model SAW propagation for any multilayer stack consisting of homogeneous layers
- 1 to 3 material parameters can be obtained from fitting data to model
- Number of material parameters that can be fitted depend on curvature of dispersion curve
- Other parameters can be derived from data bases, independent measurement or assumption



# Dispersion Curve Analysis – Number of independent parameters

## Material

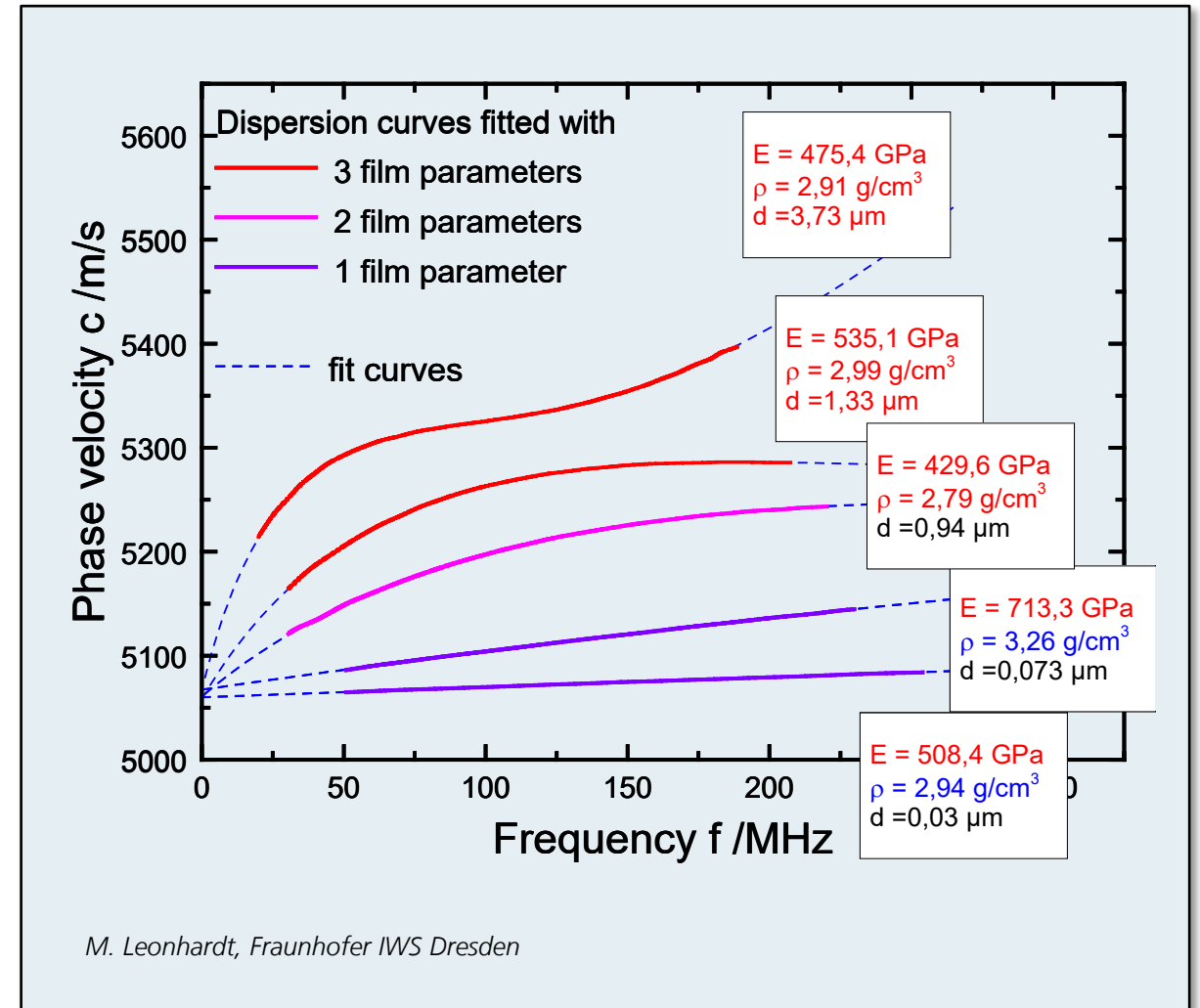
- Coating: ta-C = superhard amorphous carbon
- Substrate: Si wafer

## Film parameters that can be measured

- Young's modulus  $E$
- Density  $\rho$
- Film thickness  $d$

## More coating parameters can be fitted for

- High differences of coating and substrate
- High frequency range





# Development and Background

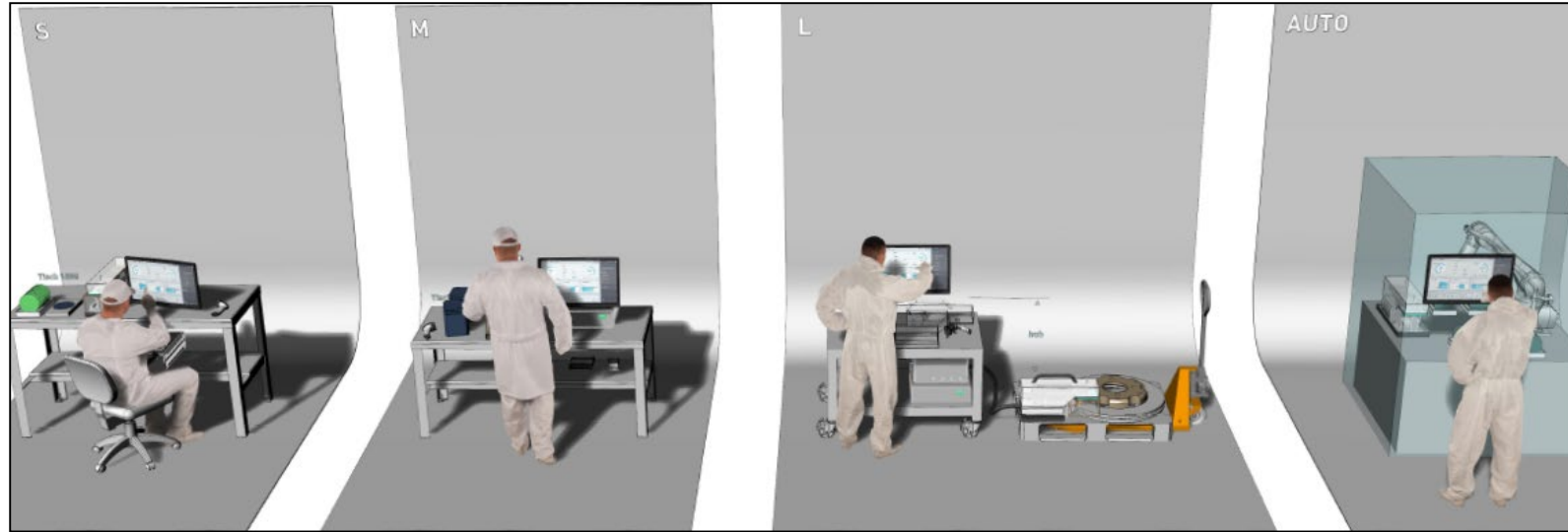
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# Current Developments

## Development topics

- Quality control suitability: automated measurement and evaluation functionality
- Mobile head for robot or hand for measurement on large parts
- Measurement at elevated temperature
- Integration for customer-specific applications

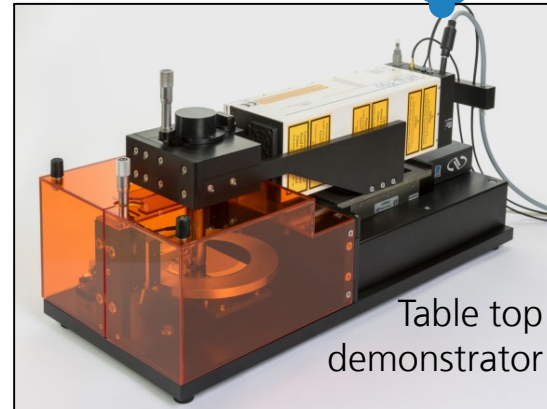
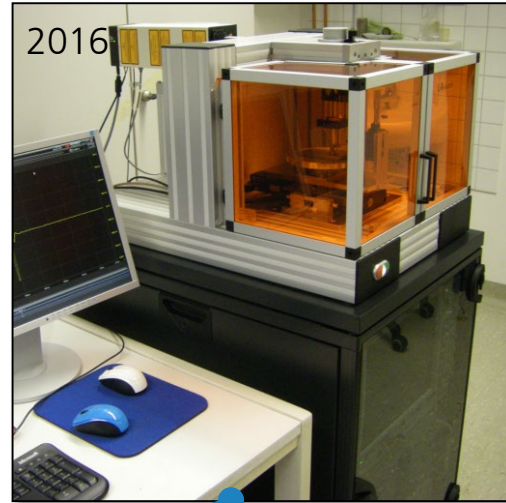
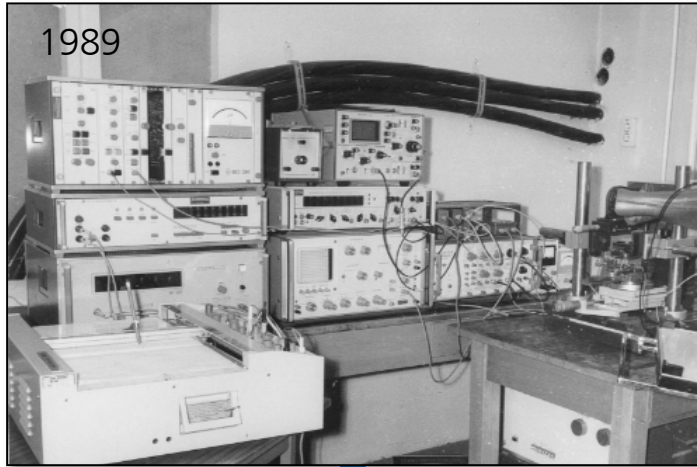


## Scaling concept for LWave system technology

From left to right

- Fully manual operated R&D tool
- Half-automated quality control system
- Quality control system for large components
- Fully automated quality control tool

# History of System Development





# Case Studies

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# Application - Overview

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## Young's modulus, thickness, density of

- All kinds of coatings: PVD, CVD, spin coating, thermal-spraying, cladding, electroplating, ...
- E.g. amorphous carbon coatings (DLC), nitrides, carbides, oxides, other ceramics
- Metal films
- Low-k films
- Polymeric sensor films
- Bulk materials, e.g. steel, brass, cemented carbide
- Si, GaAs semiconductors

## Depth of

- Subsurface damage from silicon wafer processing
- Surface hardening zones e.g. after metal finishing

# Case study: Very thin films < 10 nm

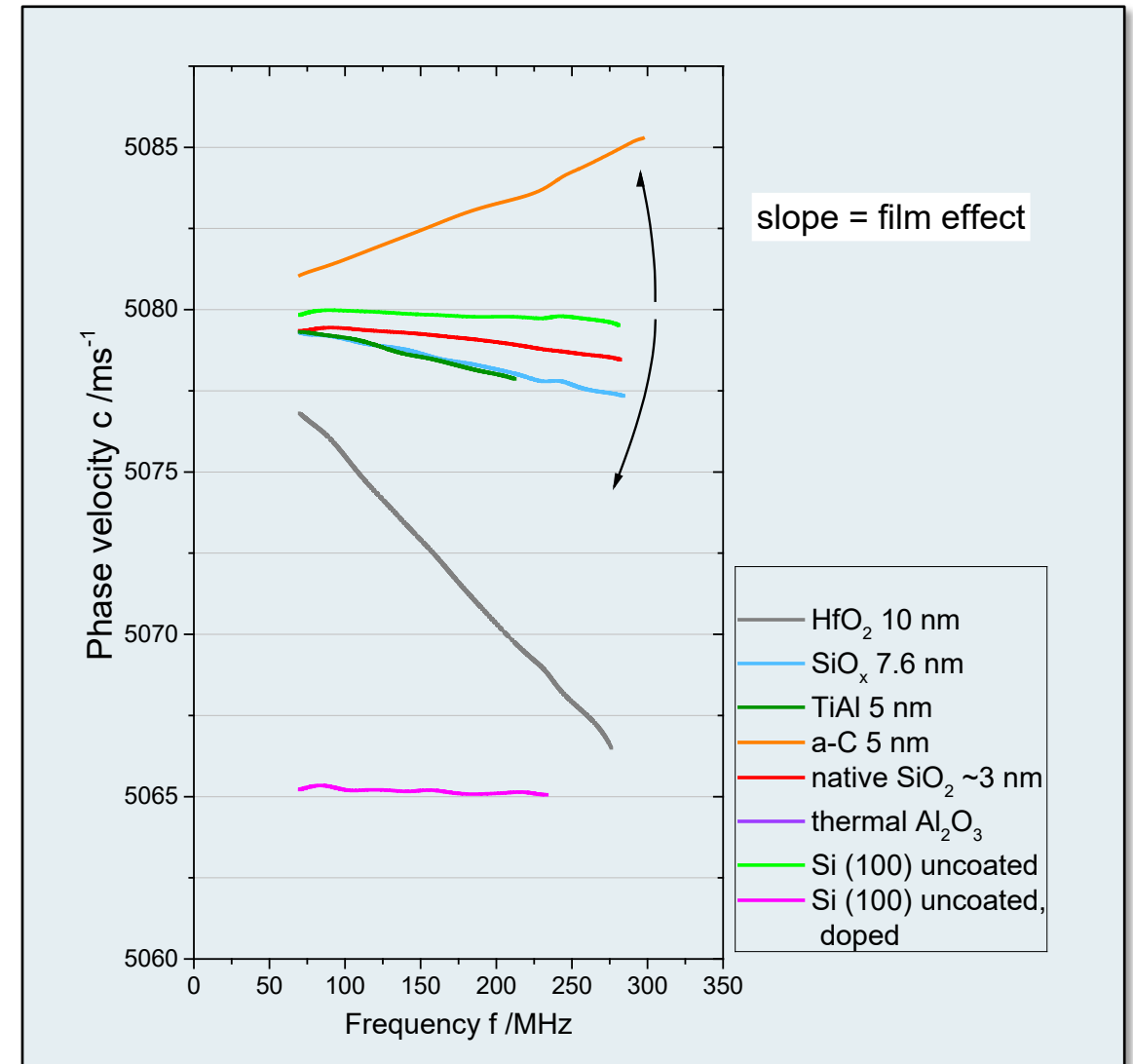
## Material

- PVD coatings with thickness < 10 nm

## Results

- Measurement of Young's Modulus
  - HfO<sub>2</sub> 220.4 GPa
  - Native SiO<sub>2</sub> 39.8 GPa
  - SiO<sub>x</sub> 41.7 GPa
  - a-C 373.4 GPa
  - TiAlN 142.8 GPa
  - Silicon wafer 165.2 GPa (C11)
  - Silicon wafer (high doping) 162.9 GPa (C11)
- Measurement of thickness of Si/Al/Al<sub>2</sub>O<sub>3</sub> multilayer stack
  - Thermal Al<sub>2</sub>O<sub>3</sub> 3.9 nm

➔ Possibilities beyond nanoindentation



# Case study: Quality control of superhard carbon coatings

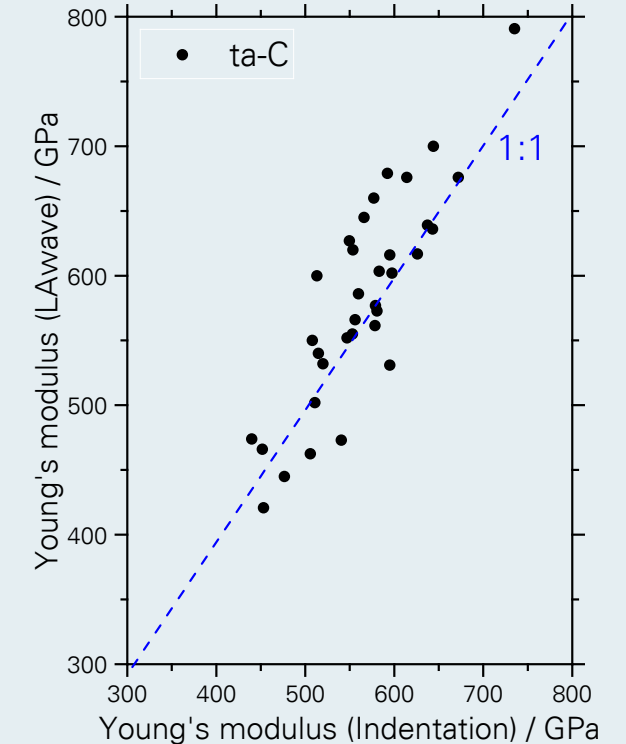
## Material

- Superhard amorphous carbon coatings (ta-C, H-free DLC), hardness 40..70 GPa
- Application: Low-wear low-friction coating, e.g. piston pins in ICE, motorcycle chain
- State-of-the art: Nanoindentation → slow and error-prone technique with high indenter wear

## Results

- LAwave allows to access
  - Coating modulus, coating hardness
  - Coating thickness

*in less than 60 seconds*



# Case study: Lateral cracks in SHVOF coatings

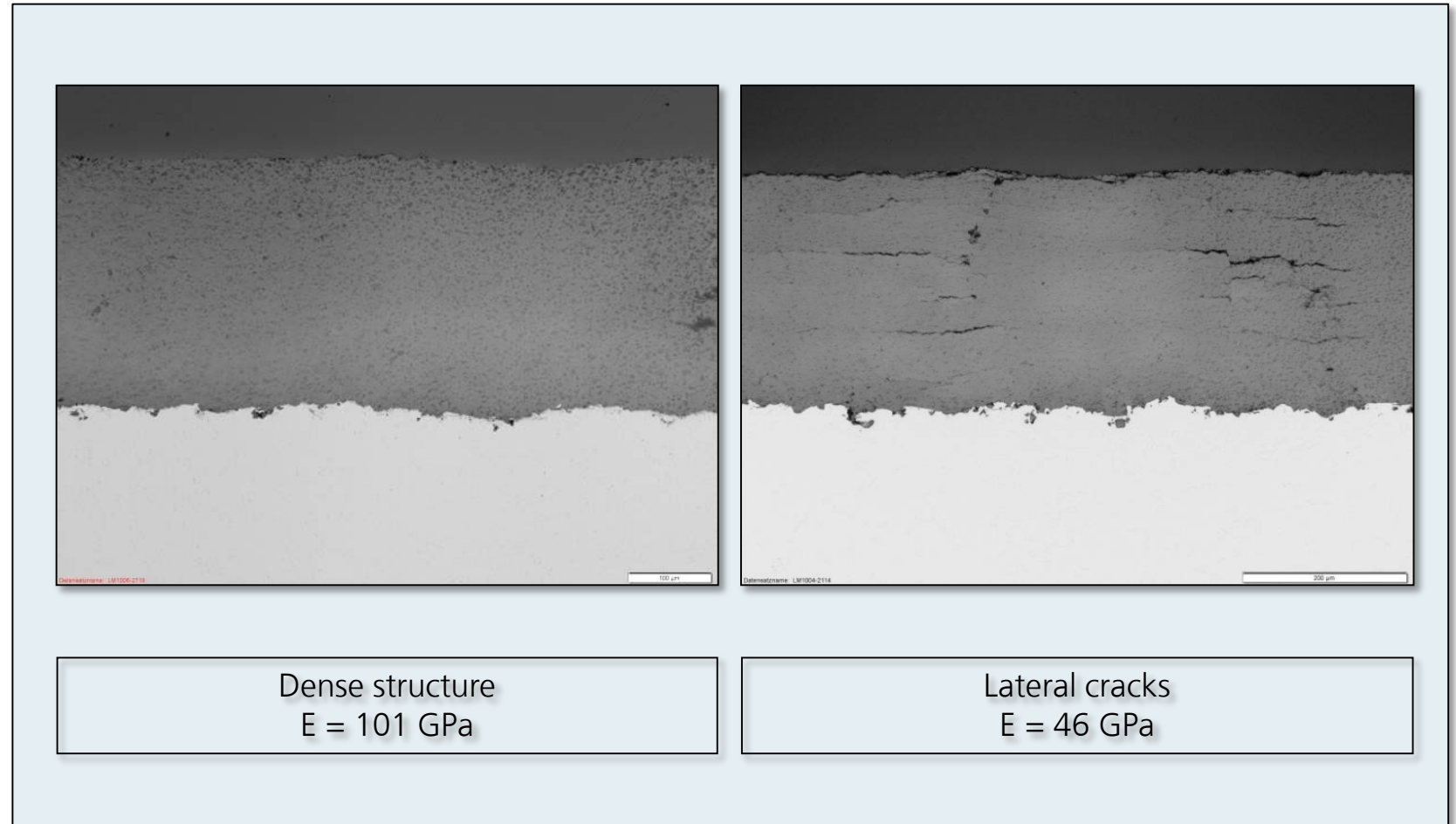
## Material

- $\text{Al}_2\text{O}_3$  SHVOF sprayed
- Thickness around 400  $\mu\text{m}$
- Coating structure: homogenous, risk of lateral cracks

## Results

- Measurement of elastic modulus
- Elastic modulus decreases due to lateral cracks

➔ **Non-destructive measurement of critical defects**



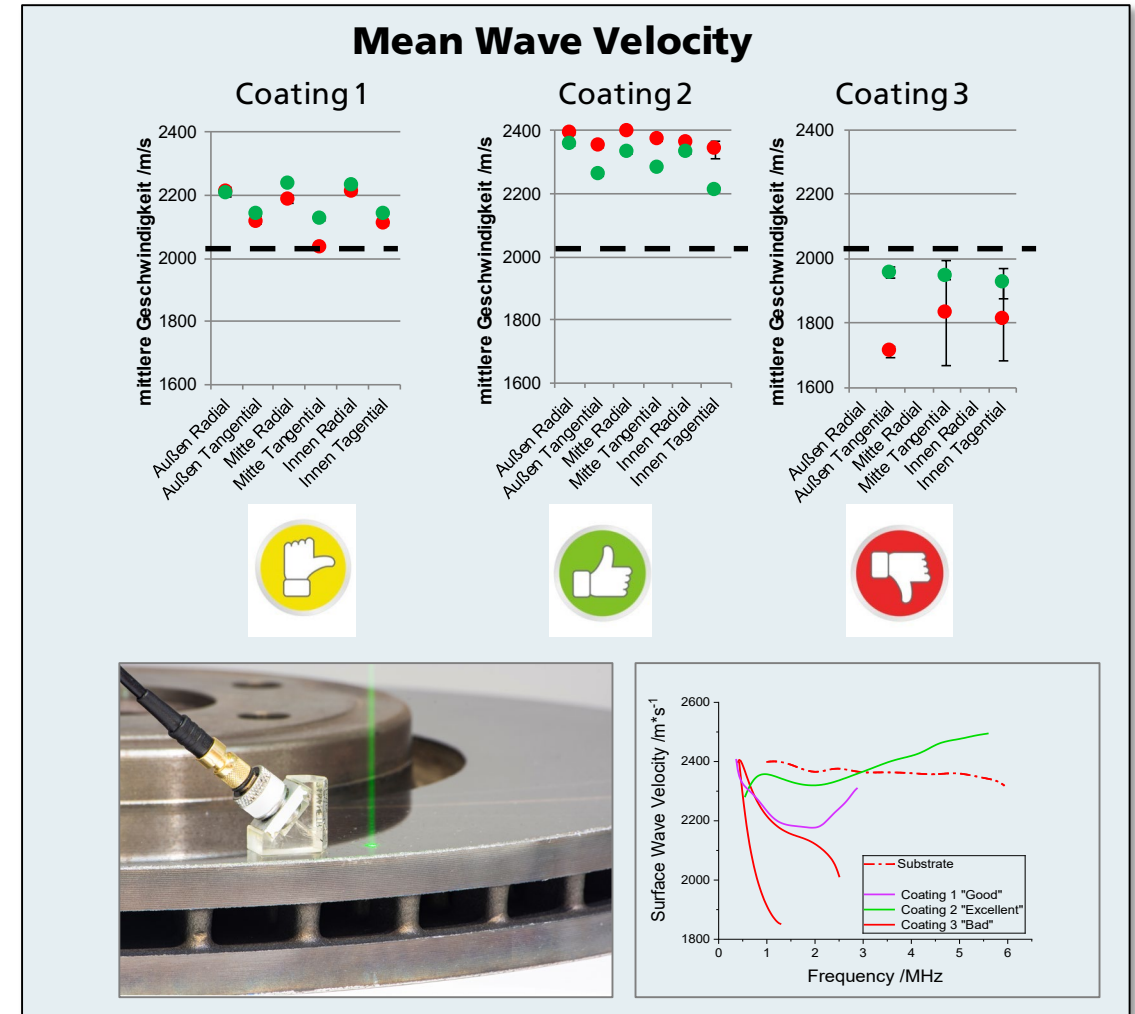
# Case study: Development of novel brake disk coatings

## Material

- Multilayer coatings from high speed laser cladding, carbides in Fe-based matrix
- Application: Novel brake disk coatings for high performance and e-mobility
- State-of-the-art: Cross section + SEM imaging → time consuming (~ hours... days), expensive, big infrastructure

## Results

- LAwave measures mechanical key features
- Front and back,  $\perp$  and  $\parallel$  to deposition direction, anywhere on the disk
- Non-destructive (disk can be measured before and after test bench)
- six representative spots measured in less than 30 minutes





# Case study: Defects in APS- $\text{Al}_2\text{O}_3$

## Material

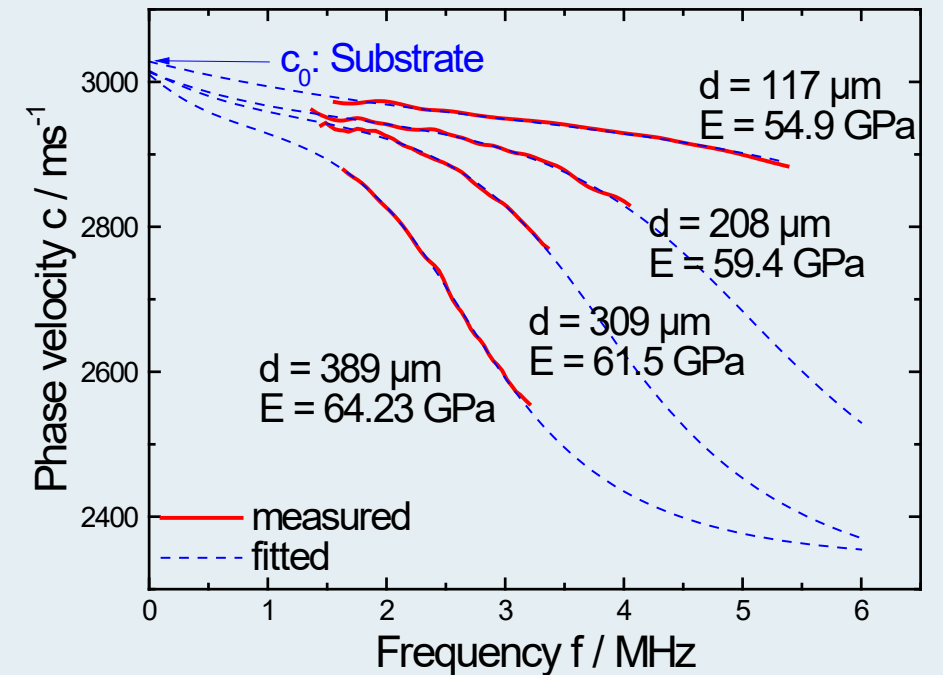
- Spray technologies: APS (or HVOF, ...)
- $\text{Al}_2\text{O}_3$  (or  $\text{Cr}_2\text{O}_3$ ,  $\text{TiO}_2$ , ...)
- Thickness 100 to 600  $\mu\text{m}$
- High roughness  $R_a > 1 \mu\text{m}$
- Coating structure: micro-cracks and porosity

## Results

- LAwave measurement gives coating thickness and effective elastic modulus  $E$
  - Effective elastic modulus varies due to different crack and pore density
- ➔ **Quality and mechanical behavior of coating can be measured non-destructively**

## $\text{Al}_2\text{O}_3$ (APS) on steel

$E$  (tabulated; compact material) = 350 GPa

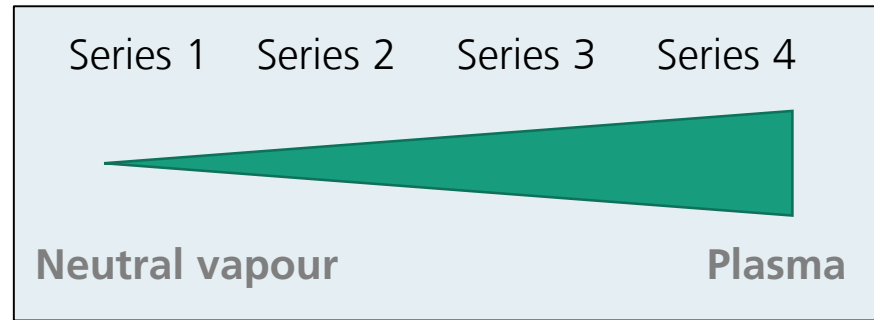


*L.-M. Berger et. al.: VIP-Journal Vol. 24, 2012*

# Case study: Pores in metal films (1/2)

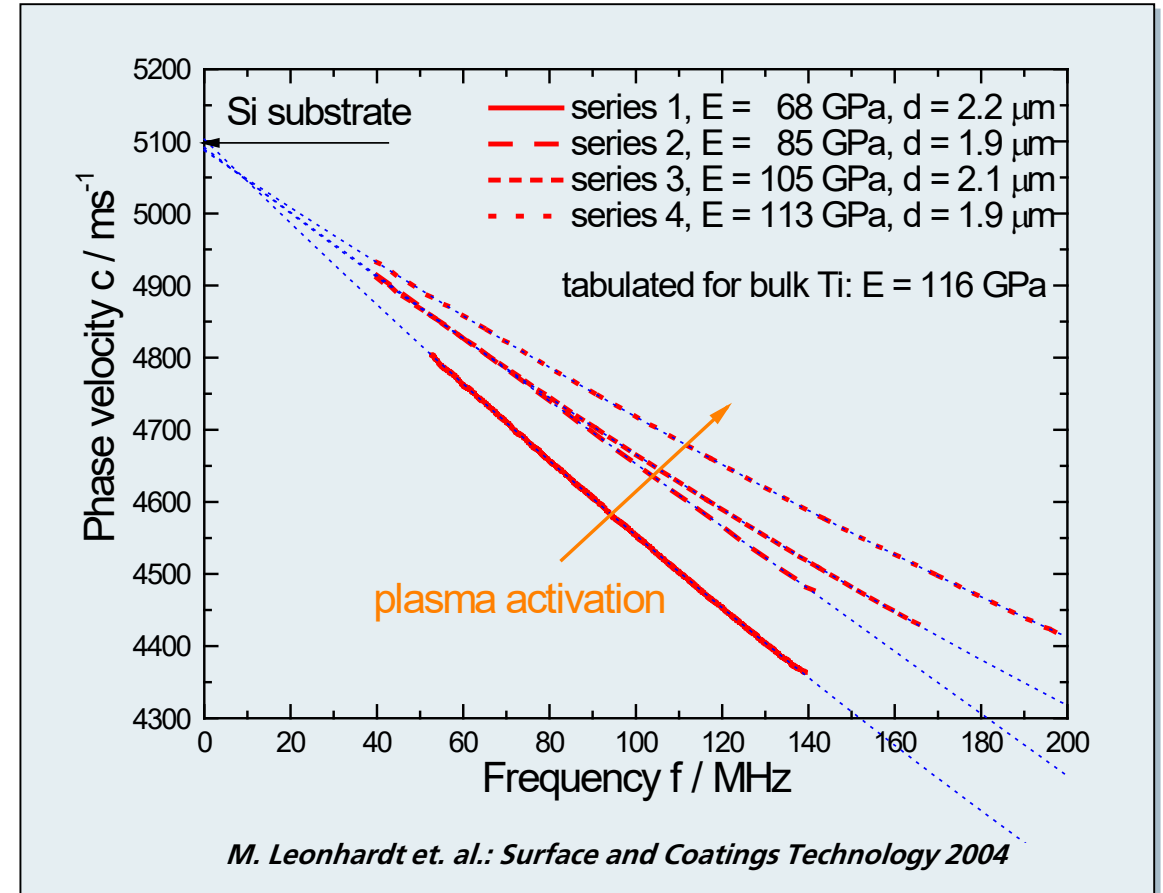
## Material

- 2  $\mu\text{m}$  Titanium coating on Si wafer
- PVD: Electron beam evaporator + additional plasma activation

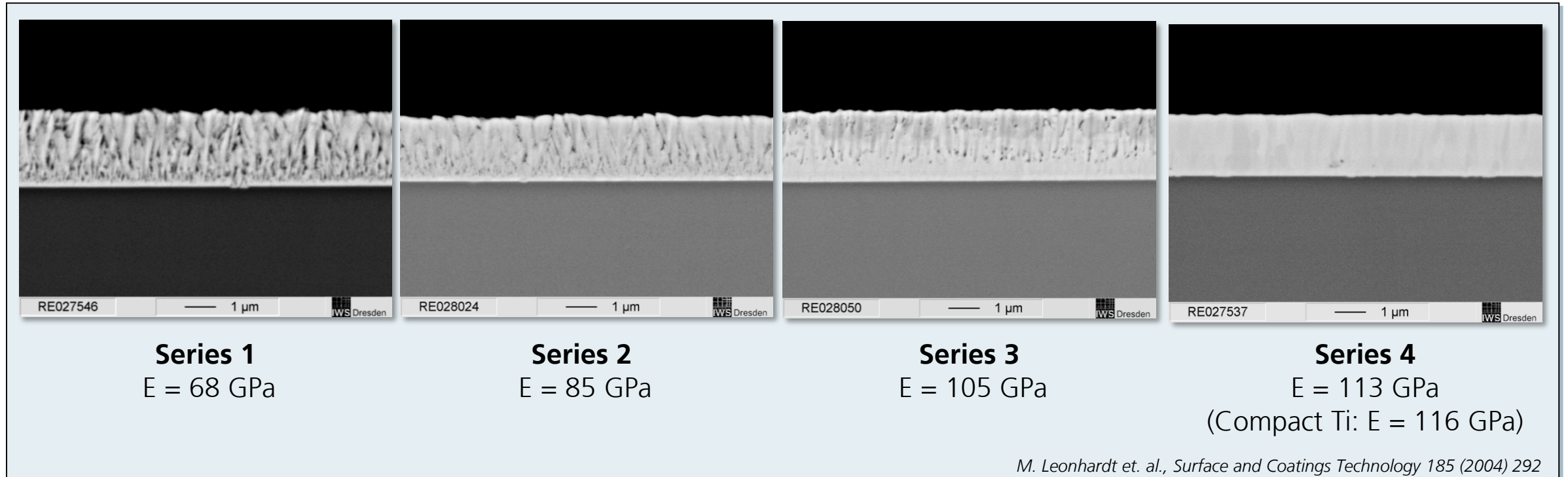


## Results

- Effective Young's Modulus is measure of porosity
- No activation  $\rightarrow$  porous films ( $E = 68 \text{ GPa}$ )
- High activation  $\rightarrow$  dense films ( $E = 113 \text{ GPa}$ )



## Example: Pores in metal films (2/2)



➔ Effective Young's Modulus strongly correlates with porosity observed in SEM cross section

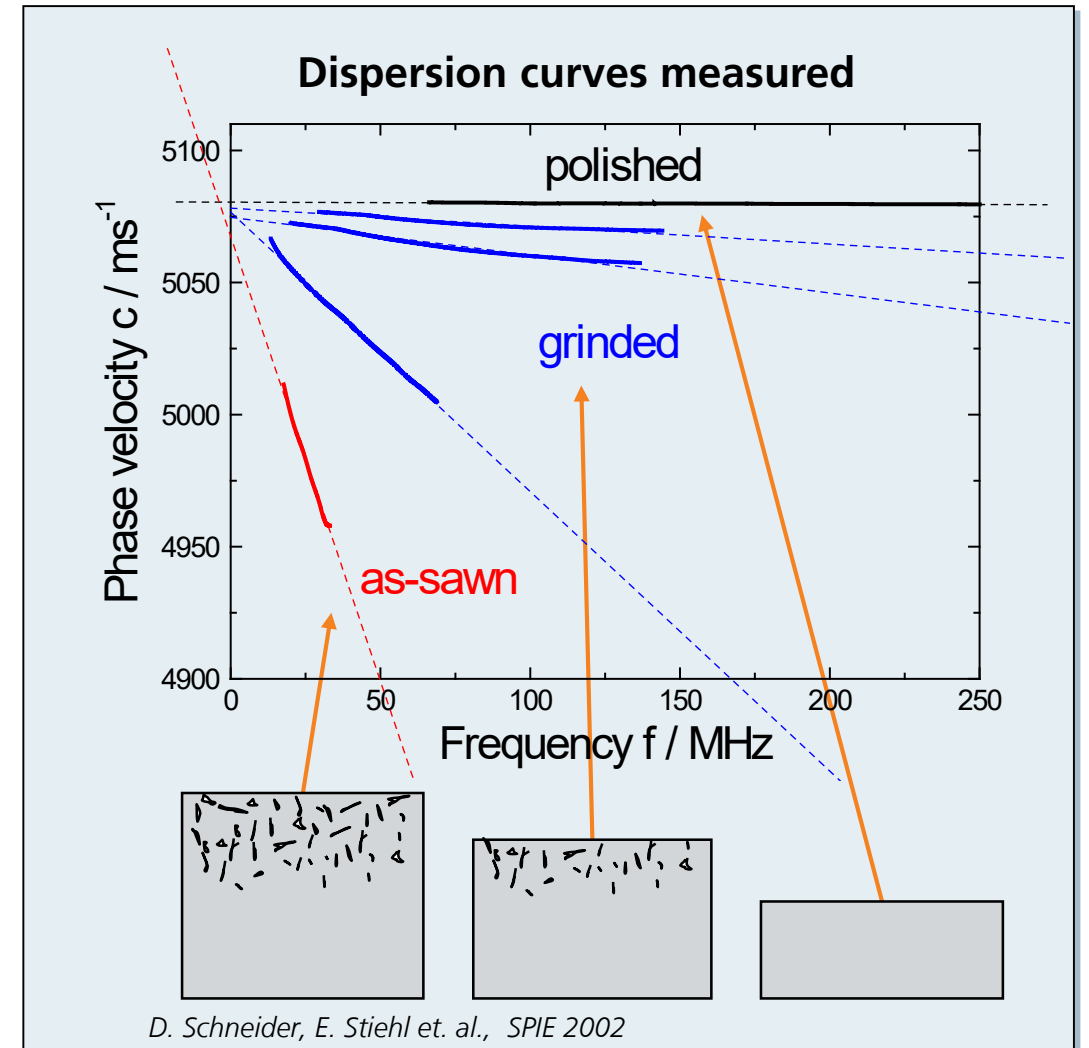
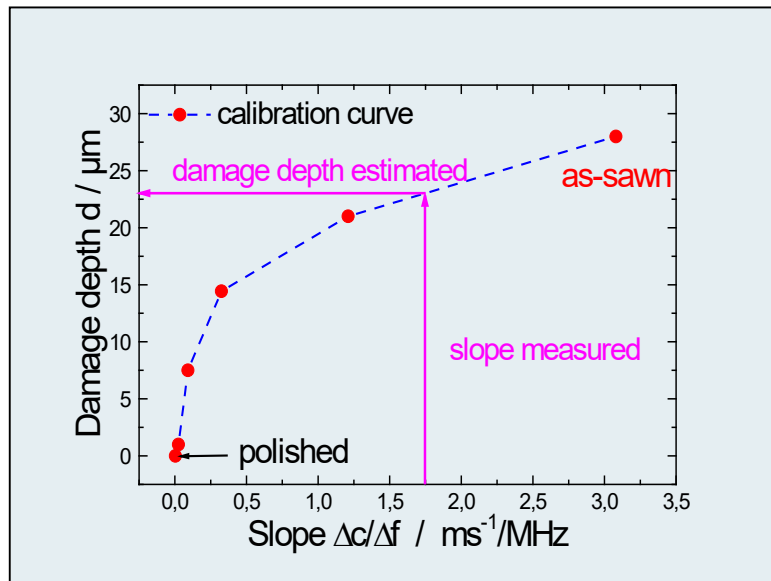
# Case study: Subsurface damage in semiconductor wafers

## Material

- Semi-conductor surfaces, damaged from processing

## Results

- Damage layer → dispersion
- Slope = damage layer depth → allows quantification



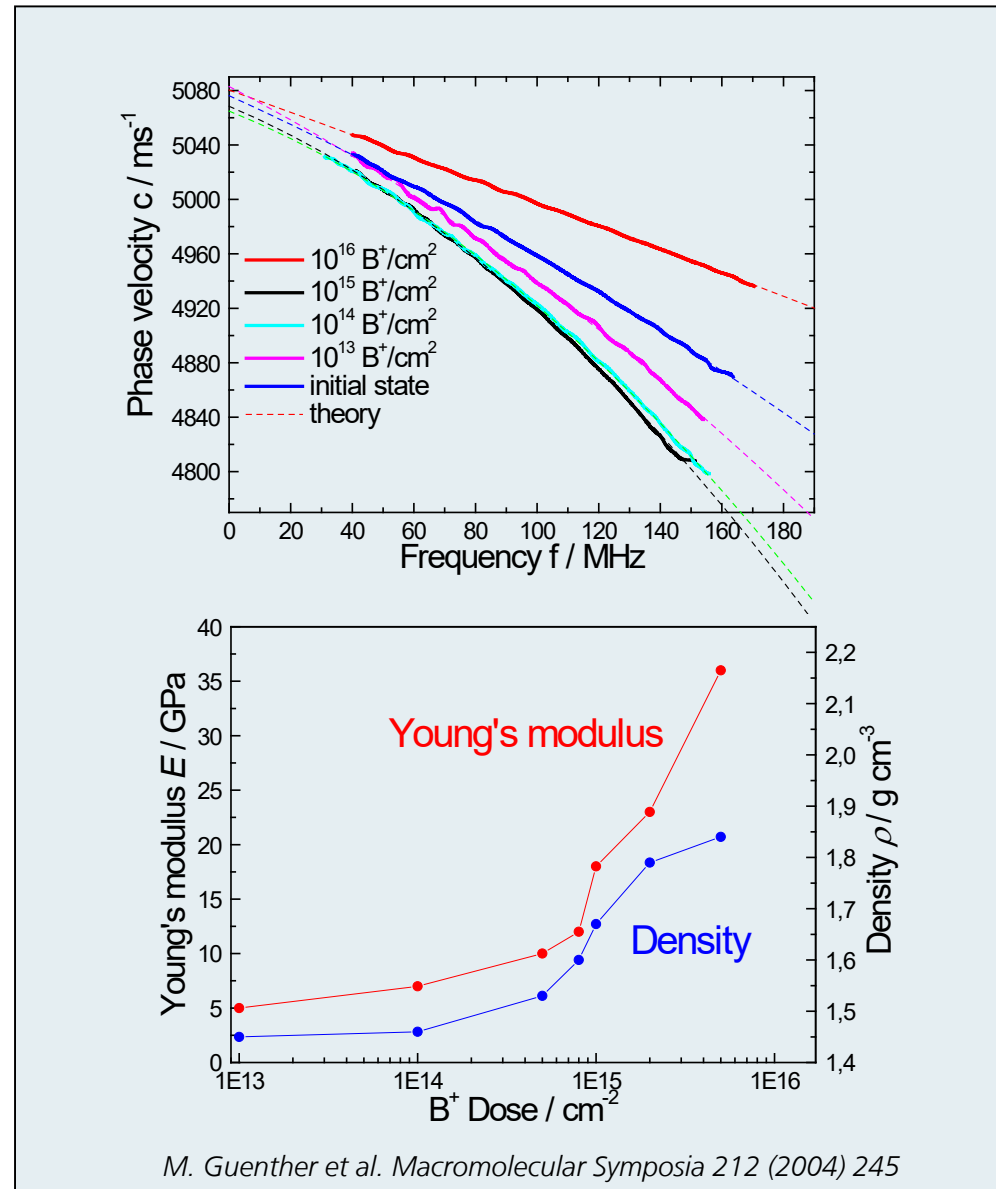
# Case study: Polymeric sensor films

## Material

- Polyimide films on silicon wafer for humidity sensors
- Film thickness 500 to 600 nm
- B<sup>+</sup> ion implantation to improve sensor properties

## Results

- Young's modulus  $E$  and Density  $\rho$  were obtained from the measurement
- Density and Young's modulus increase with B<sup>+</sup> dose
- Distinct effect for a B<sup>+</sup> dose > 10<sup>15</sup> B<sup>+</sup>/cm<sup>2</sup>
- Young's modulus increased by approx. 700 %



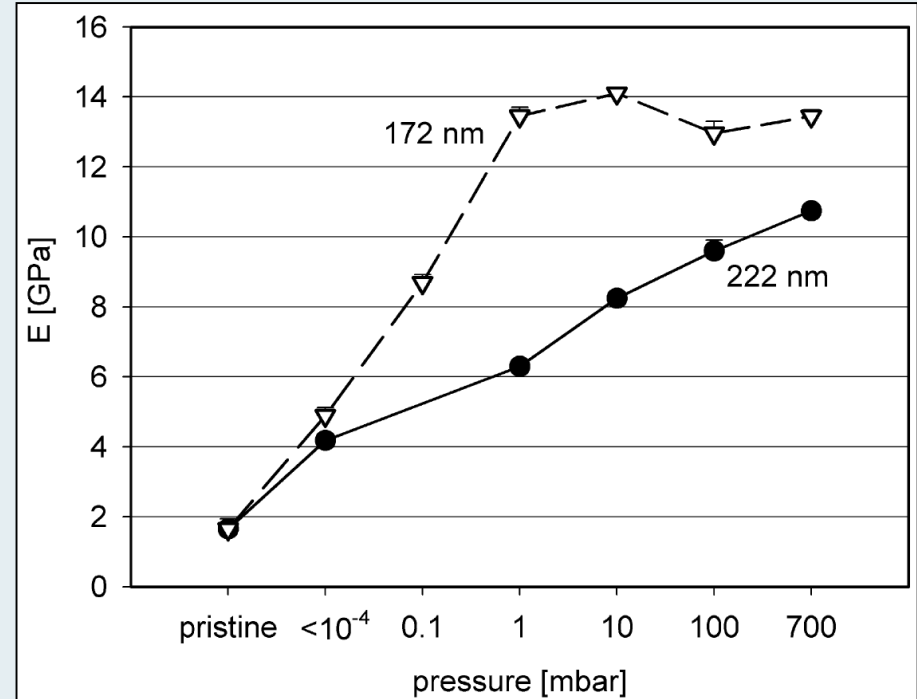
# Example: Porous low-k films

## Material

- Nano-porous SiCOH low-k films
- High porosity: > 40 %
- Rel. permittivity  $k < 2.5$
- Minimum required stiffness  $E > 5$  GPa

## Results

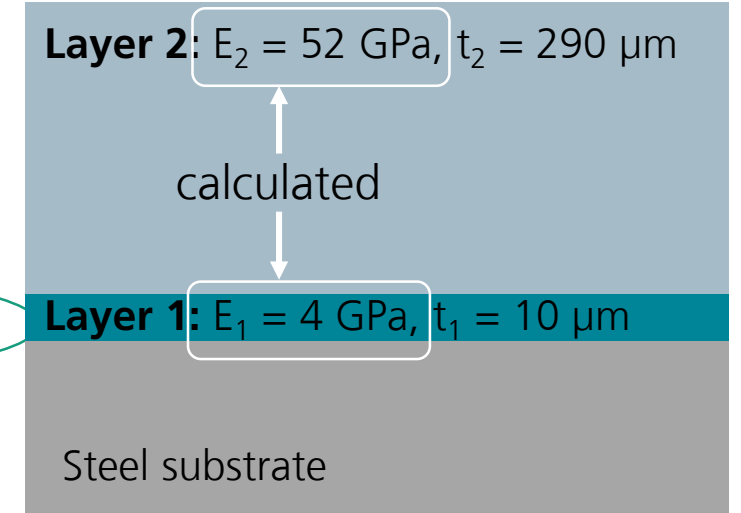
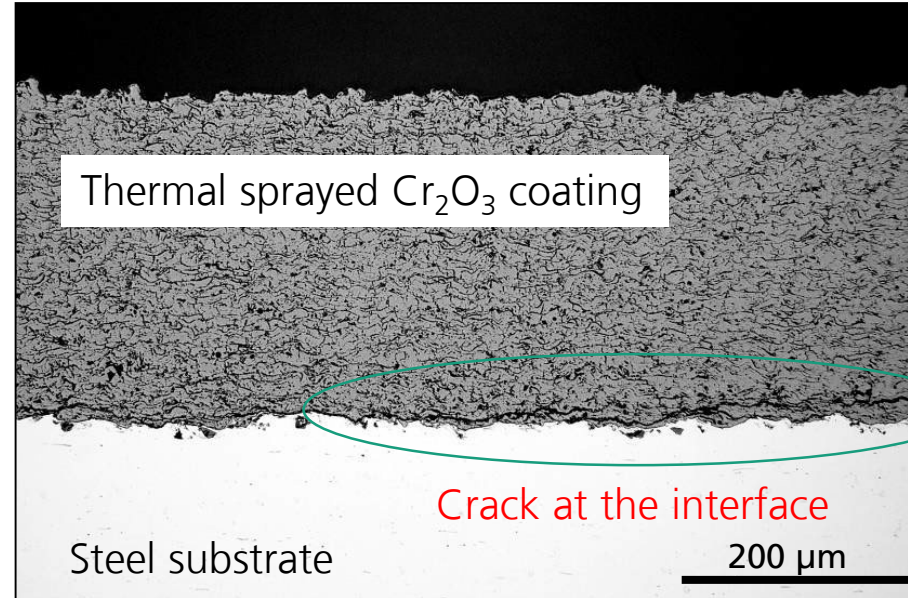
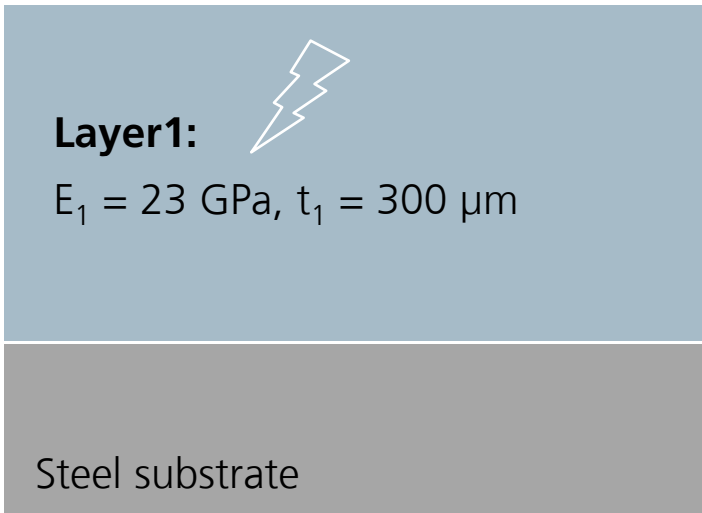
- Young's modulus and density can be measured
- Higher reliability than results from nanoindentation



Irradiation with 172 nm and 222 nm photons,  $\rho = 1.2$   $\text{gcm}^{-3}$  and  $d = 200$  nm

Prager et al. *Microelectronic Engineering* 85 (2008) 2094–2097

# Case study: Delaminations



## 1<sup>st</sup> step: simple 1-layer model

- Measured Young's modulus smaller than expected ( $E = 50 \text{ GPa}$ )
- Measurement and model do not fit

## 2<sup>nd</sup> step: cross section preparation

- Delamination revealed at interface

## 3<sup>rd</sup> step: 2-layer model

- 2-layer model fits expectation when weak interface is assumed

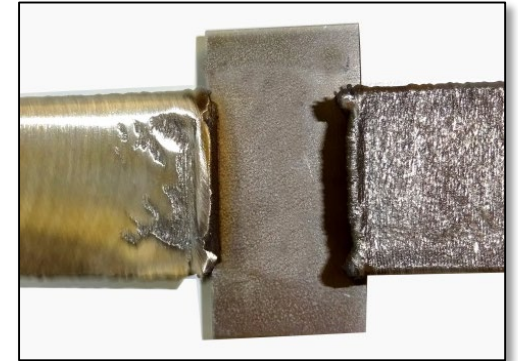
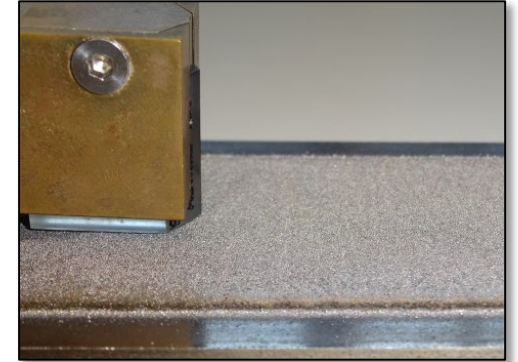
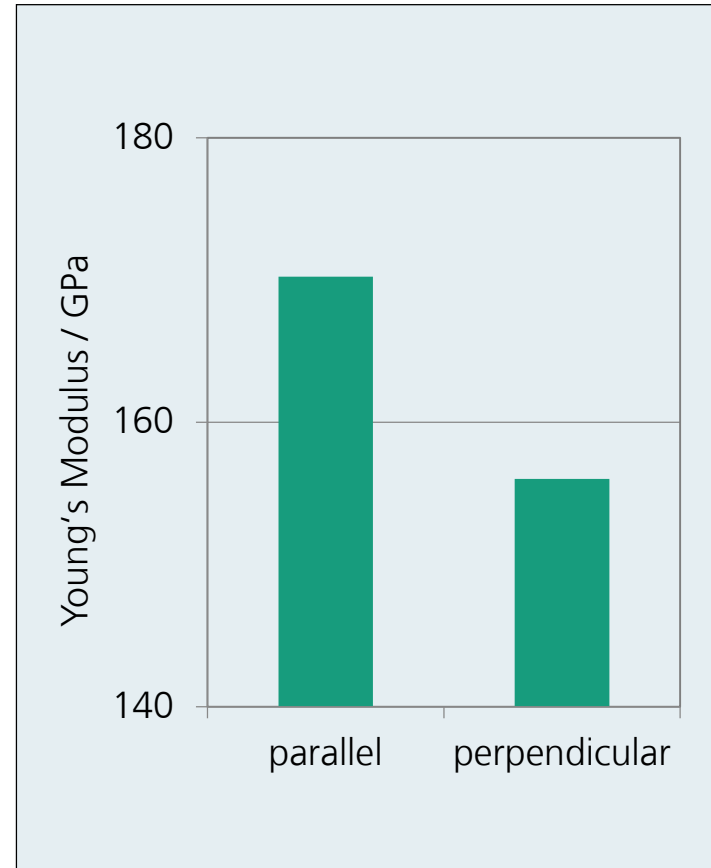
# Case study: Laser cladding, laser buildup welding

## Material

- Coatings from Laser Cladding on steel, thickness: 0,5 ... 2 mm
- Bulk samples from Laser Buildup Welding
- e.g. Inconel 625, 316 L
- High roughness  $R_a > 1 \mu\text{m}$

## Results

- Young's Modulus from measurement
- Influence of buildup direction ( $\perp$  or  $\parallel$  to cladding lines)
- Microstructure: Influence of cracks and porosity





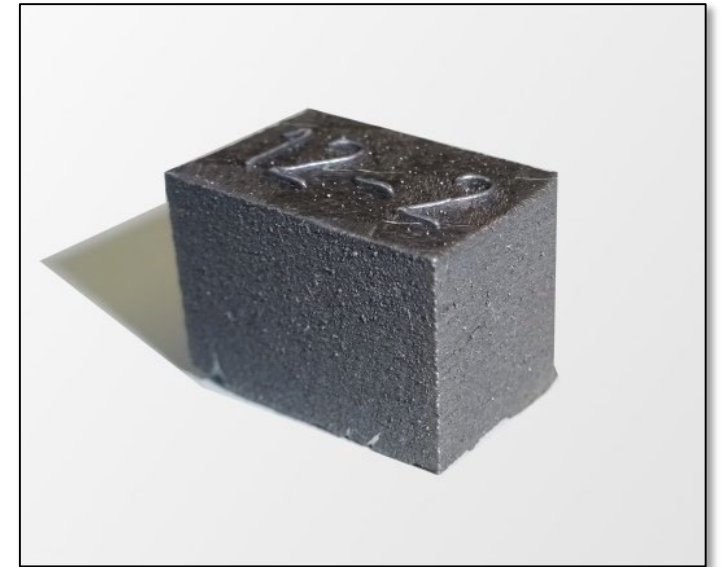
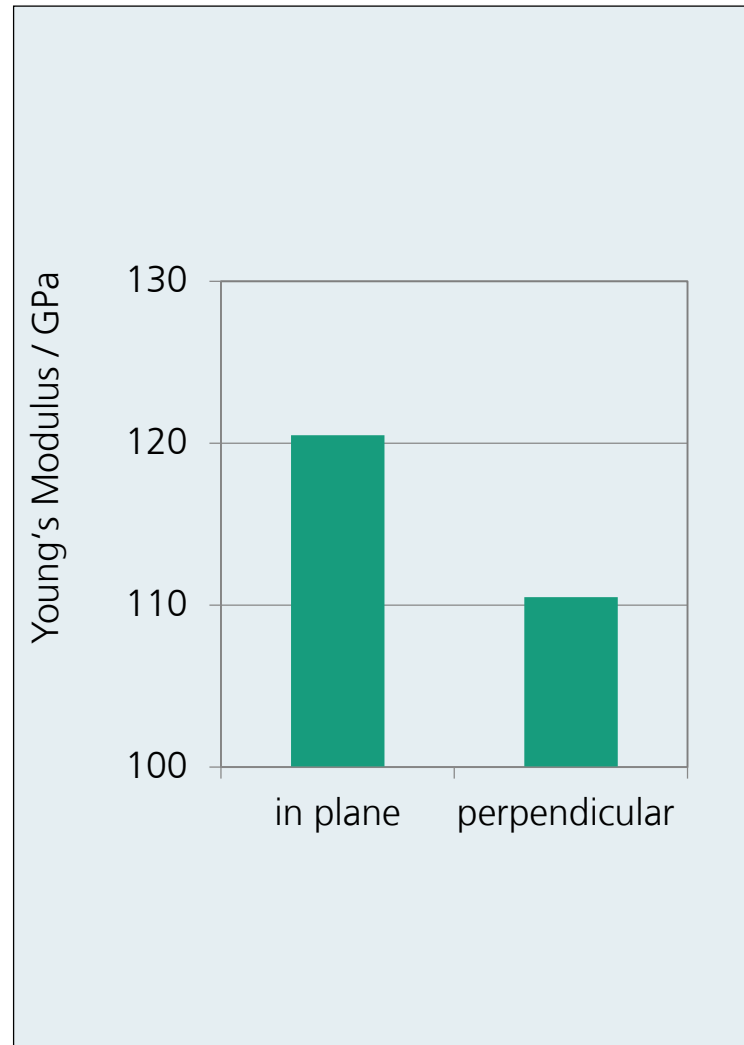
# Case study: Parts generated from Selective Laser Melting (SLM)

## Material

- Parts generated by selective laser melting
- Material: e.g. AlSi40, Ti6Al4V, ...

## Results

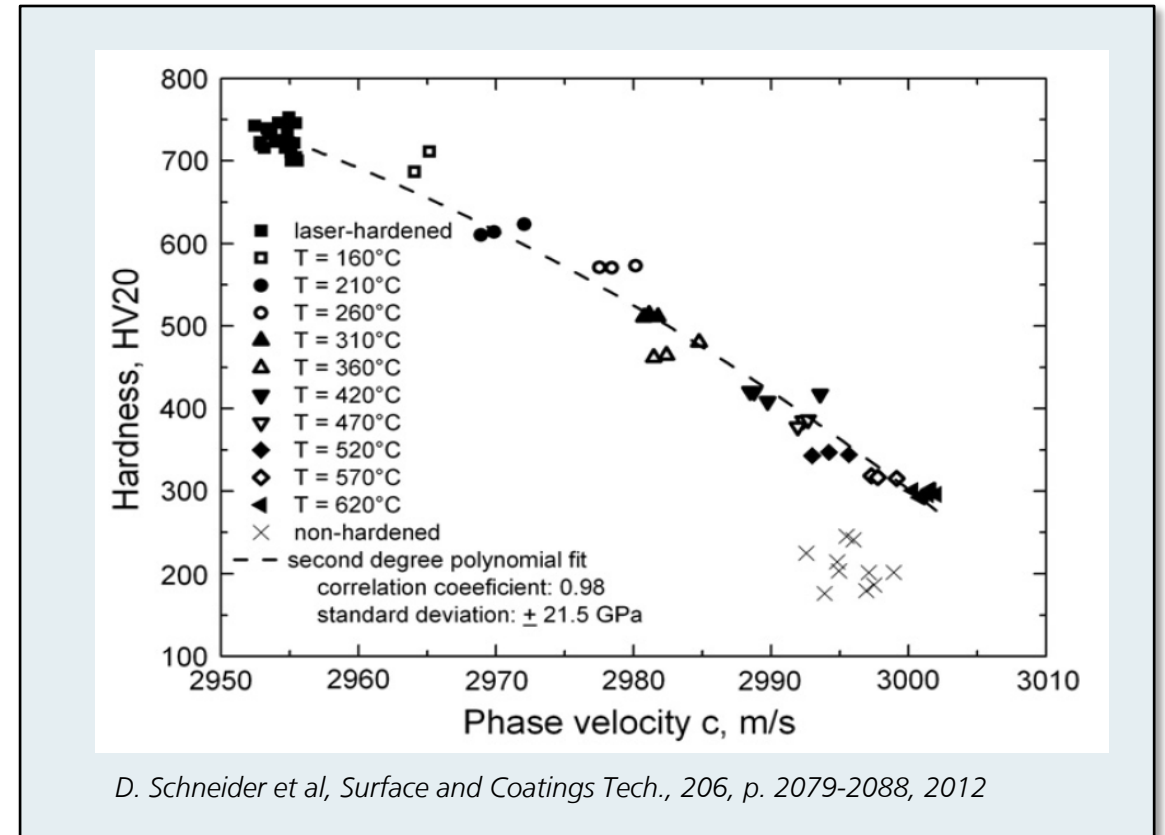
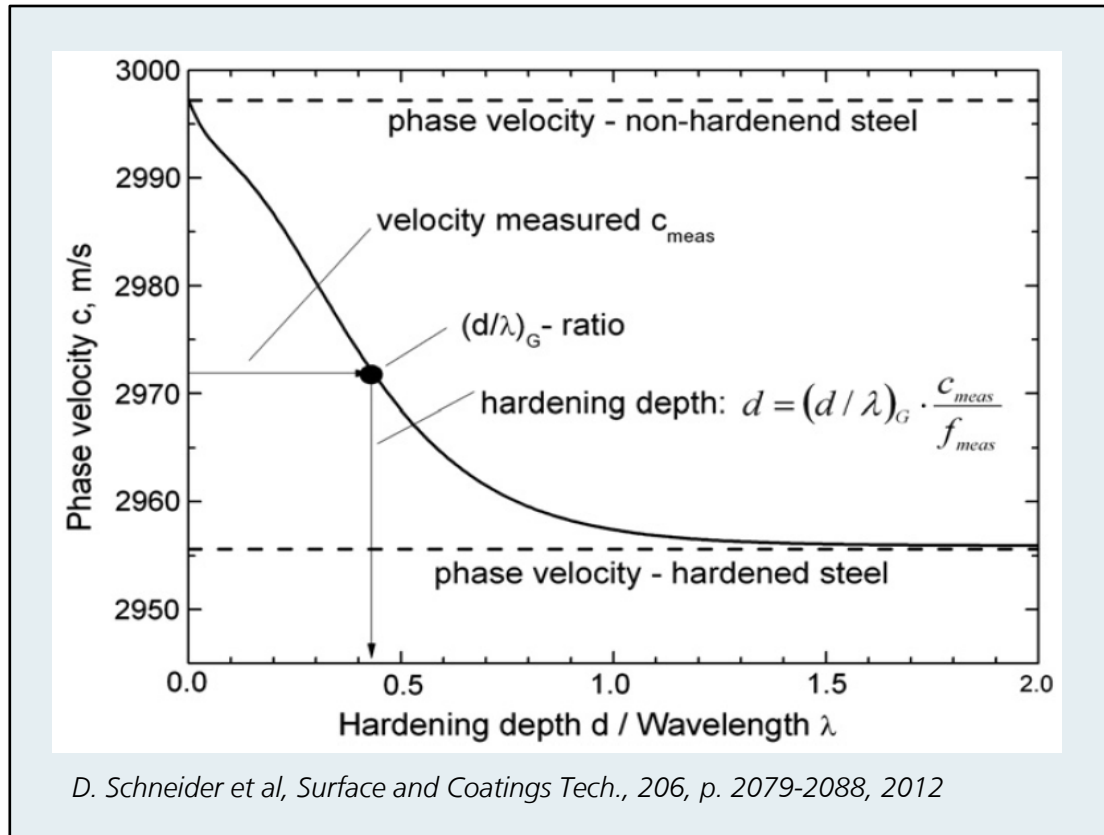
- Young's modulus
- Influence of buildup direction ( $\perp$  or  $\parallel$  to built up lines)
- Microstructure: Influence of cracks and porosity



# Case study: Hardening depth

**Material:** Surface hardened metal (case hardening, laser hardening, nitrogen hardening, ...)

**Results:** Hardening depth, surface hardness



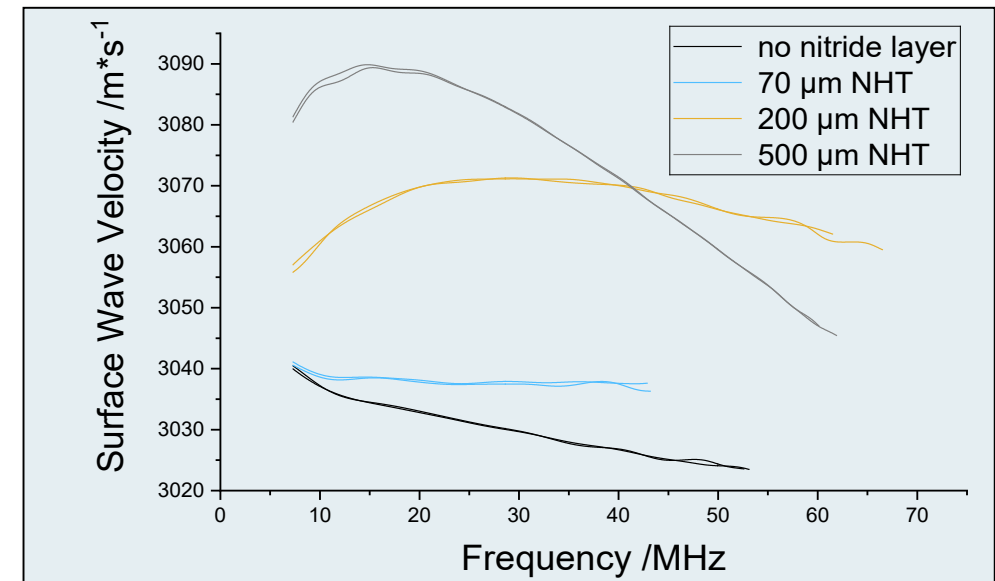
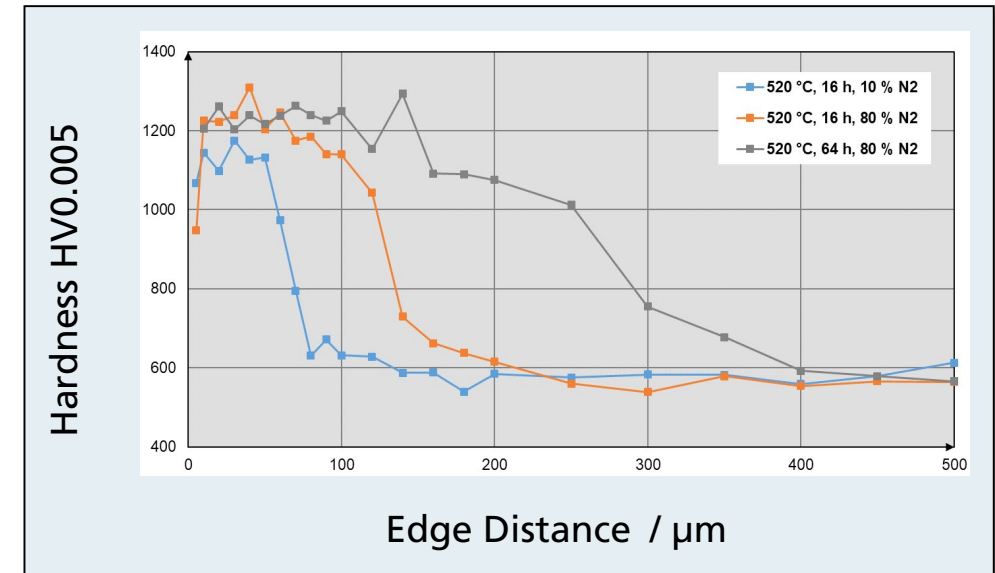
# Case study: Nitriding depth

## Material

- Steel 1.2343
- Nitrided with different nitride hardening depths (= NHT)

## Results

- Strong correlation between hardness profile and dispersion curves
- Dispersion curves hold information about NHT, surface and core hardness, and more





# Methodical Aspects

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# Measurement on native rough surfaces

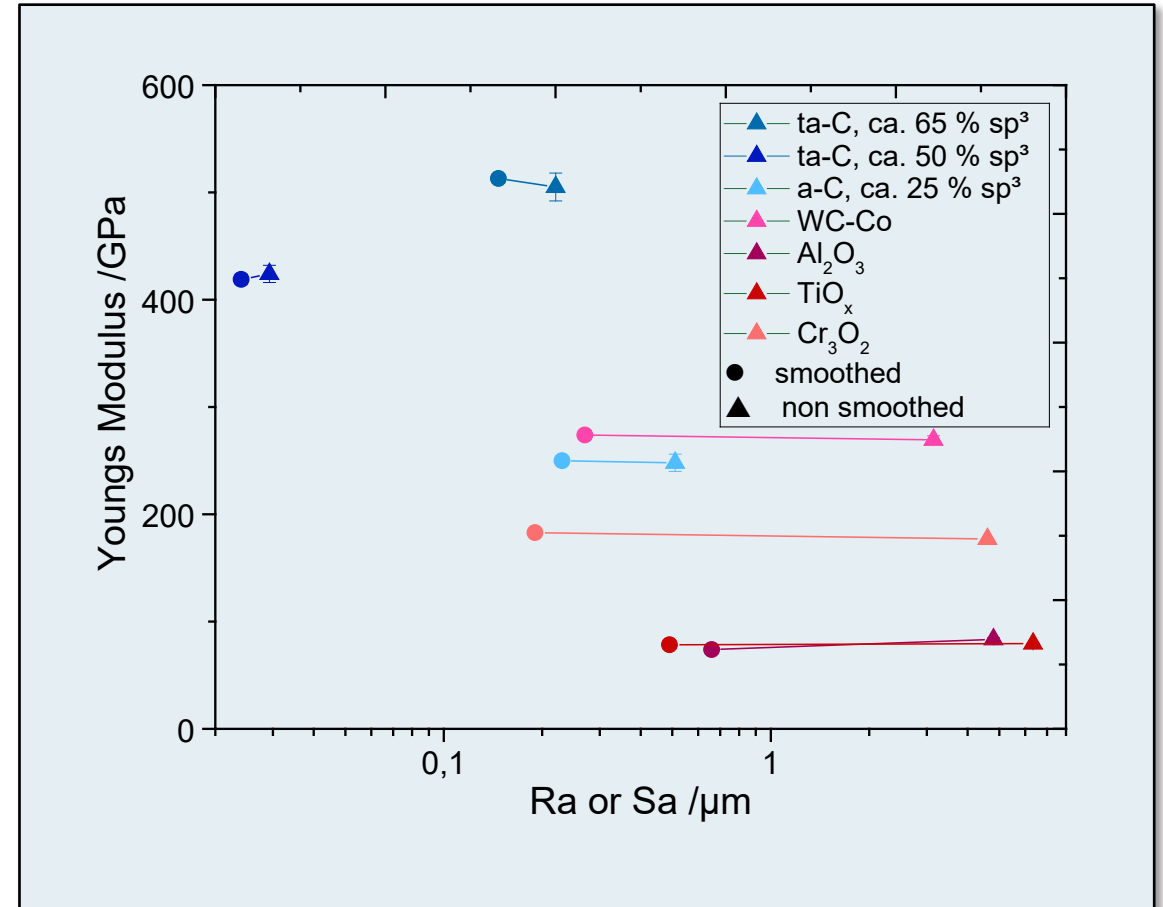
## Material

- Various hard PVD and thermal spray coatings
- Surfaces both as-deposited and smoothed

## Results

- Measurement on both surfaces conditions possible
- Young's Modulus does not change
- Condition: Roughness ( $R_a$  0,02 - 6,5  $\mu\text{m}$ )  $\ll$  wave length (ca. 50  $\mu\text{m}$  @ 60 MHz)

➔ **Measurement on native rough surfaces as reliable as on smooth surfaces**



# Influence of sample curvature

## Measurement in axial direction

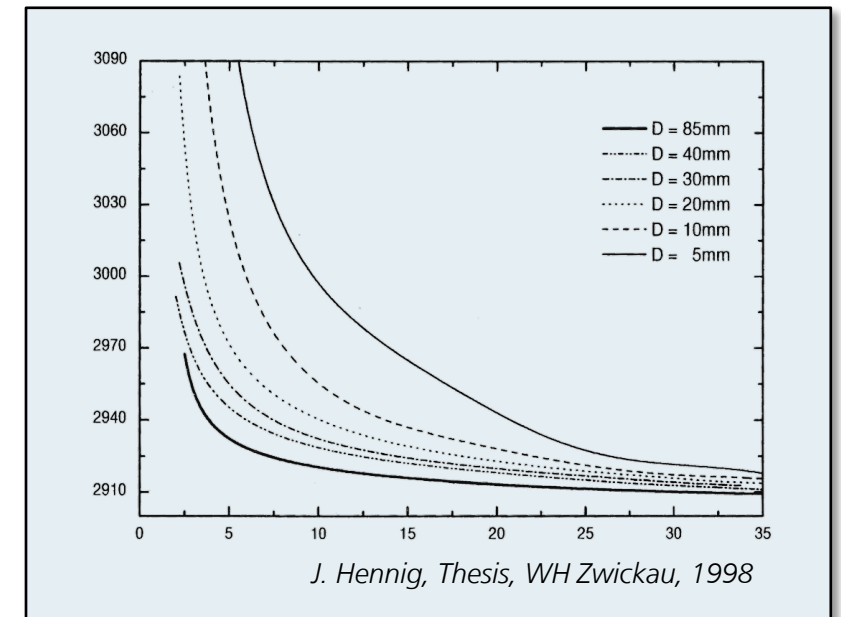
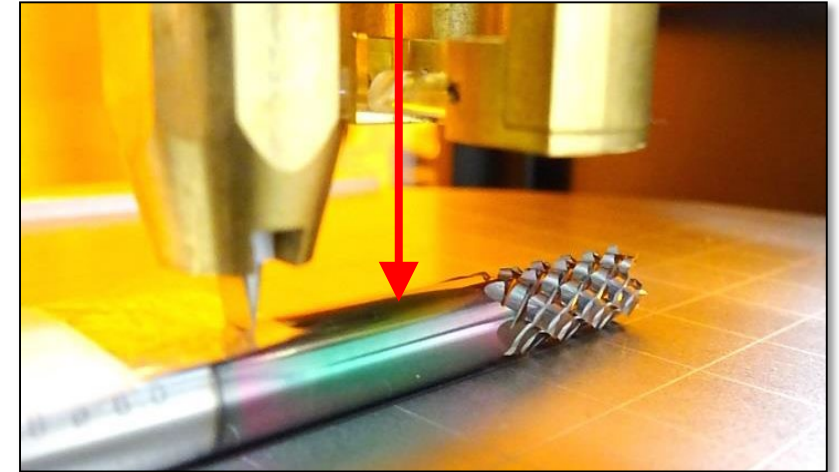
- No limitations from curvature
- Signal/noise ratio smaller

## Measurement in radial direction

- Additional dispersion from curvature at low frequencies
- Correction of the influence of curvature mathematically possible

➔ No general limitations from sample curvature

➔ Practical limitations for complex 3D structures



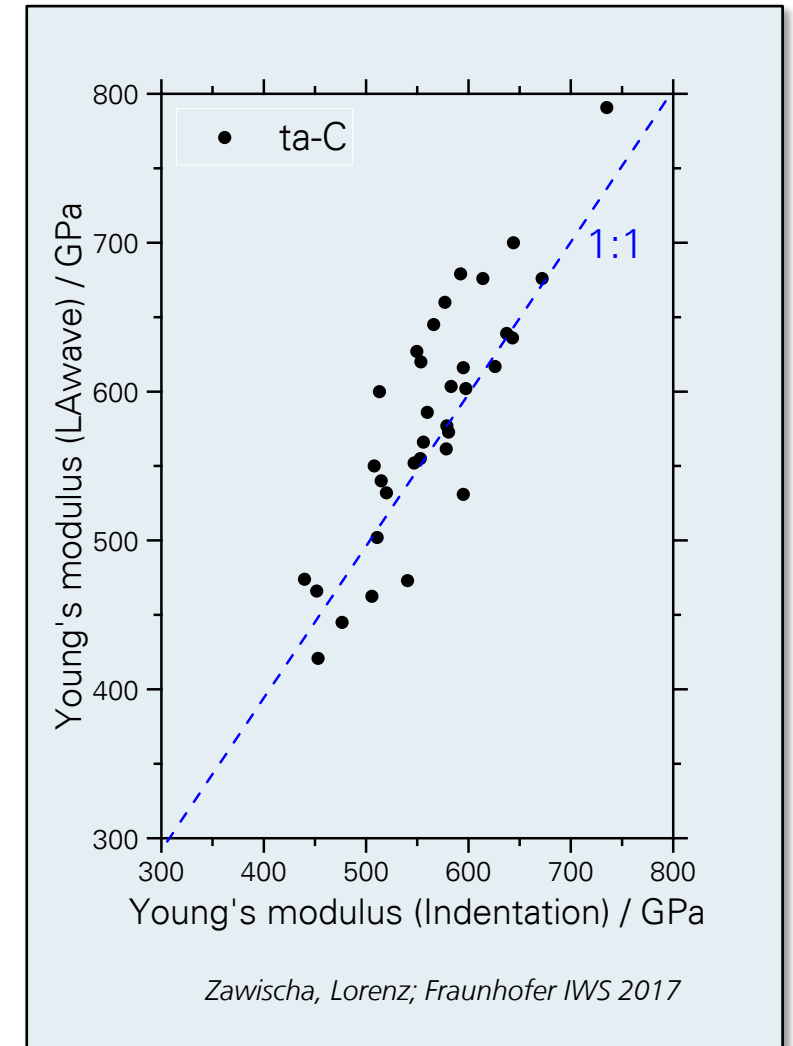
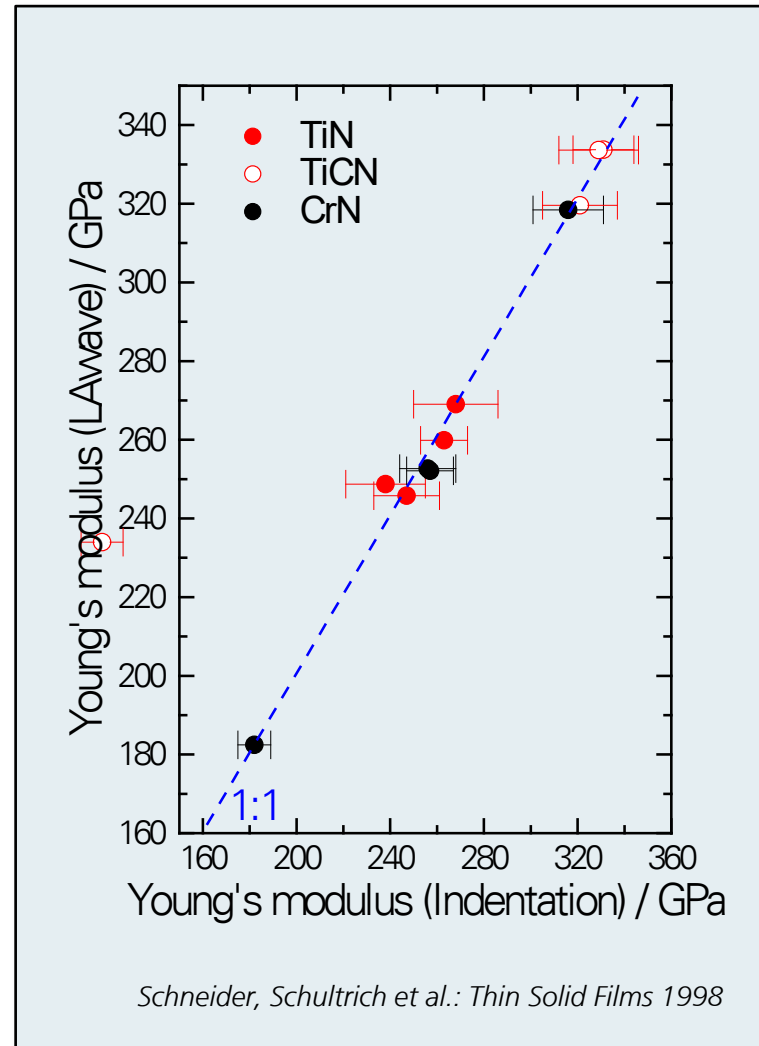
# Comparison with instrumented indentation testing

## Coating Materials

- TiN, TiCN, CrN (magnetron sputtering)
- ta-C (LaserArc)
- Film thickness:  $d > 1 \mu\text{m}$

## Result

- Excellent agreement of Young's Modulus from both methods for solid, non-porous bulk materials



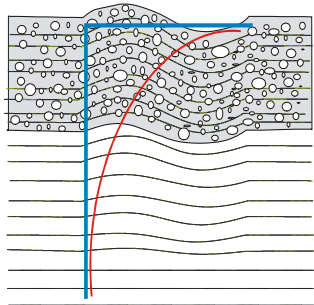
# Comparison with instrumented indentation testing

## Coating Materials

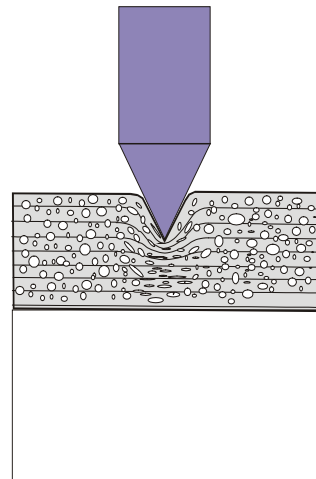
- Porous low-k films

## Result

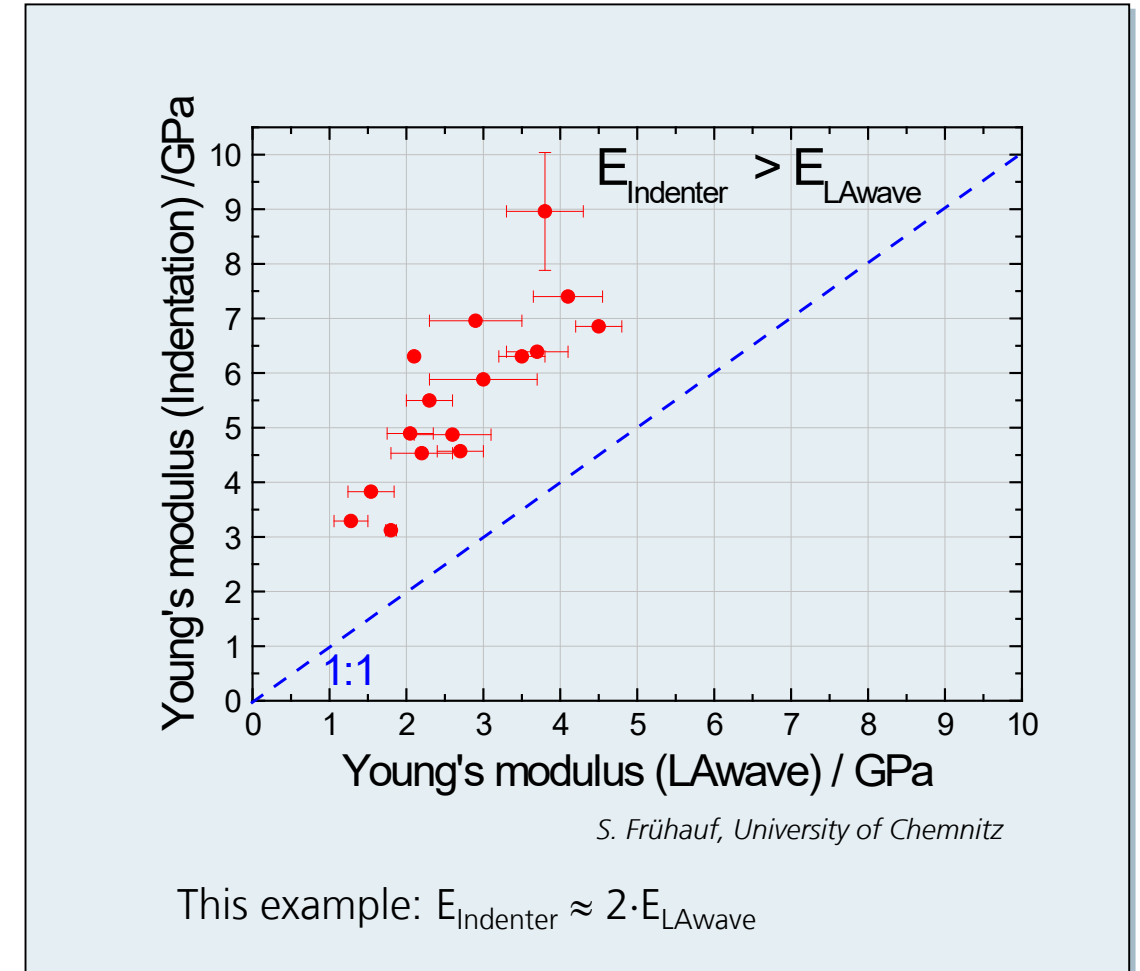
- Effective modulus is strongly overestimated with indentation due to compressed pores



**Surface acoustic waves**  
Reversible deformation  
→ True elasticity



**Indentation**  
Densification of microdefects  
→ Distorted results





# Comparison with instrumented indentation testing (nanoindentation)

	<b>LWave</b>	<b>Nanoindentation</b>
Method	Dynamic: Sound velocity $c \sim \sqrt{(E/\rho)}$	Quasi-static: $E_r \sim dP/dh$
Measuring area	> 5 x 5 mm <sup>2</sup> (integral method)	< 10 μm <sup>2</sup> (local method)
Measuring time	One minute	~ 1 hour (including sample preparation and calibration)
Minimal film thickness	A few nanometers	≈ 100 nanometers
Surface roughness	No requirements	Smooth surface necessary
Difficult material systems	Transparent and high damping materials	Soft and superhard materials, very thin coatings

➔ **LWave method has superior benefits over nanoindentation for many application scenarios**

# LWave around the world

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Image: Aris Katsaris CC BY-SA 3.0

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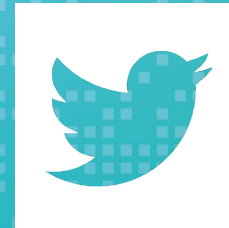
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